

1/44

11790871

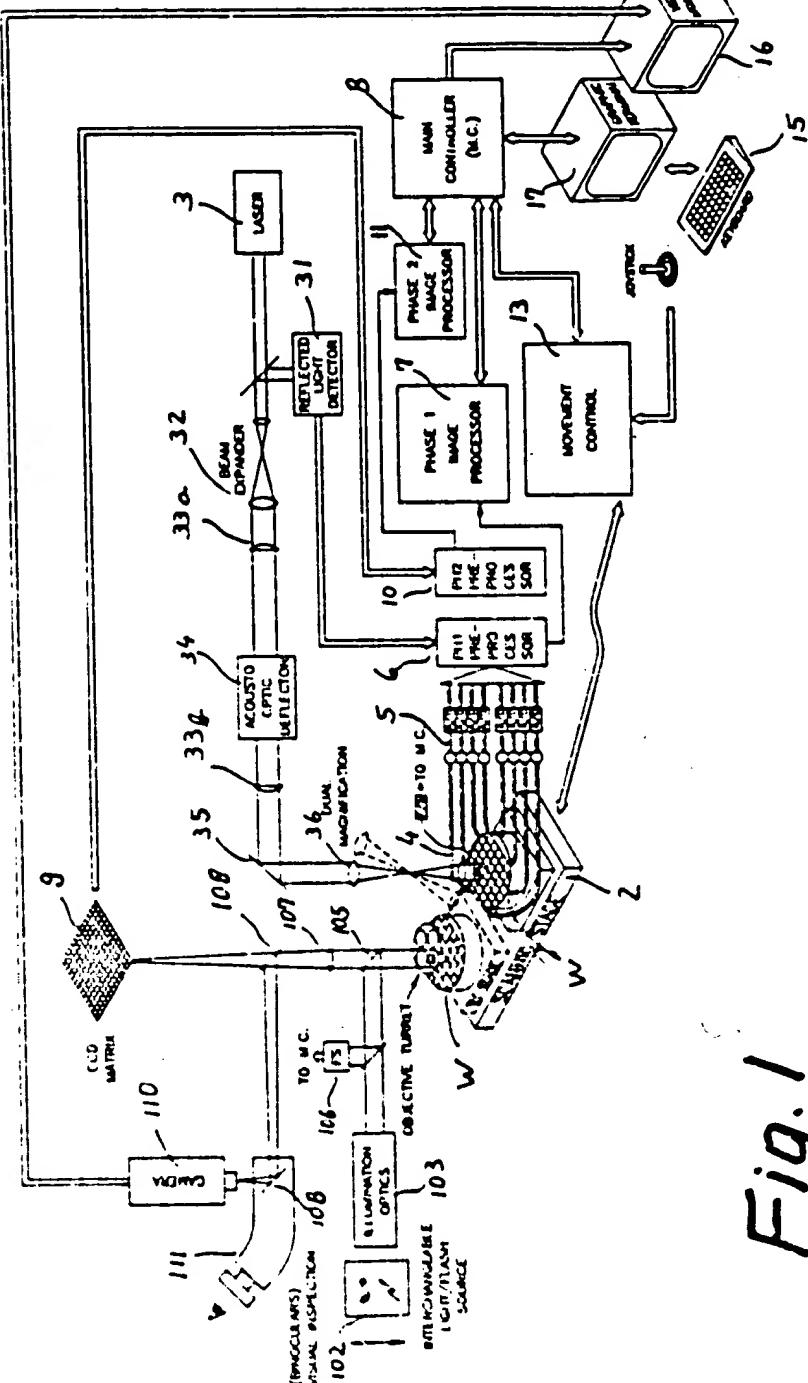
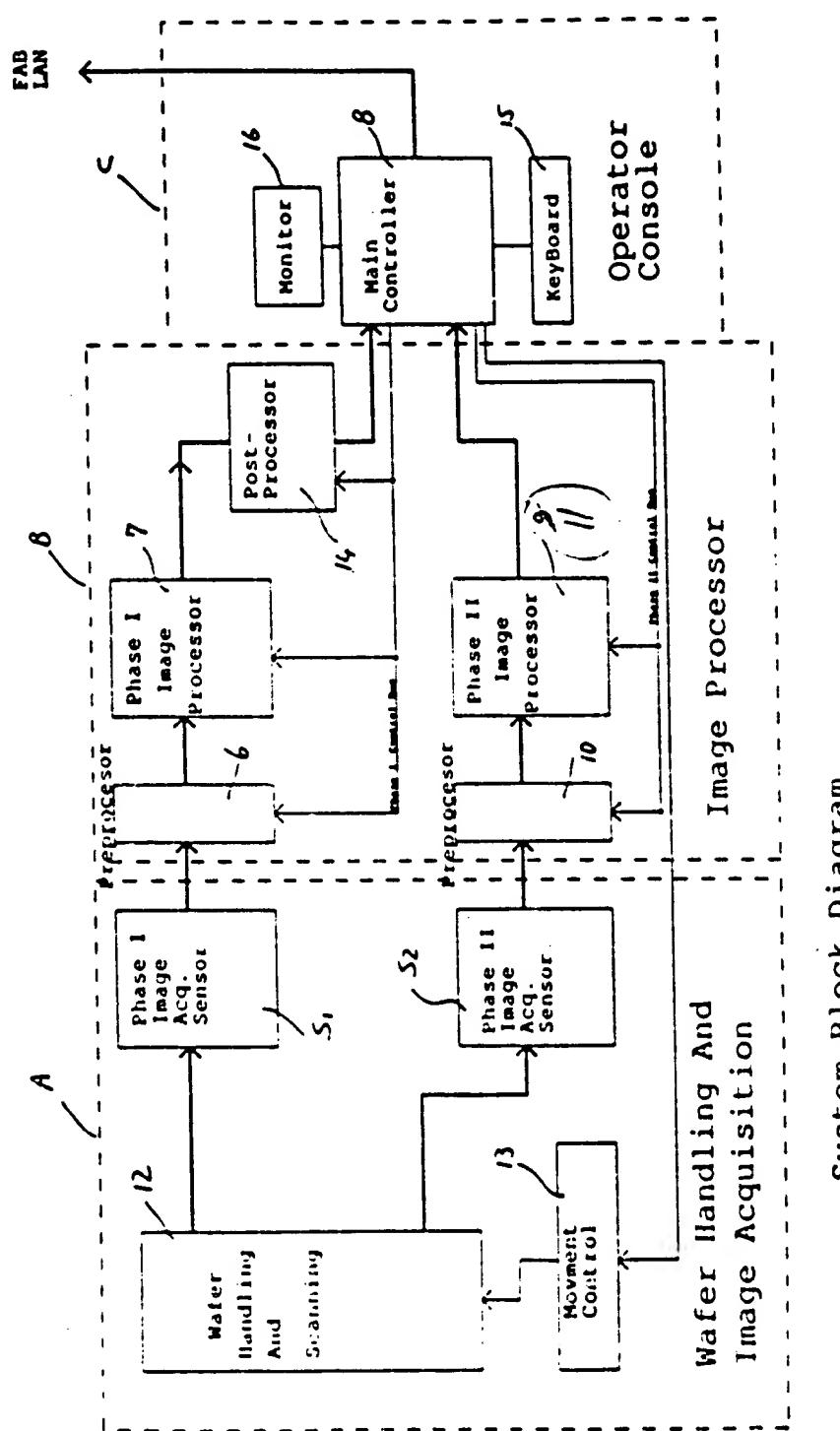


Fig. 1

BEST AVAILABLE COPY

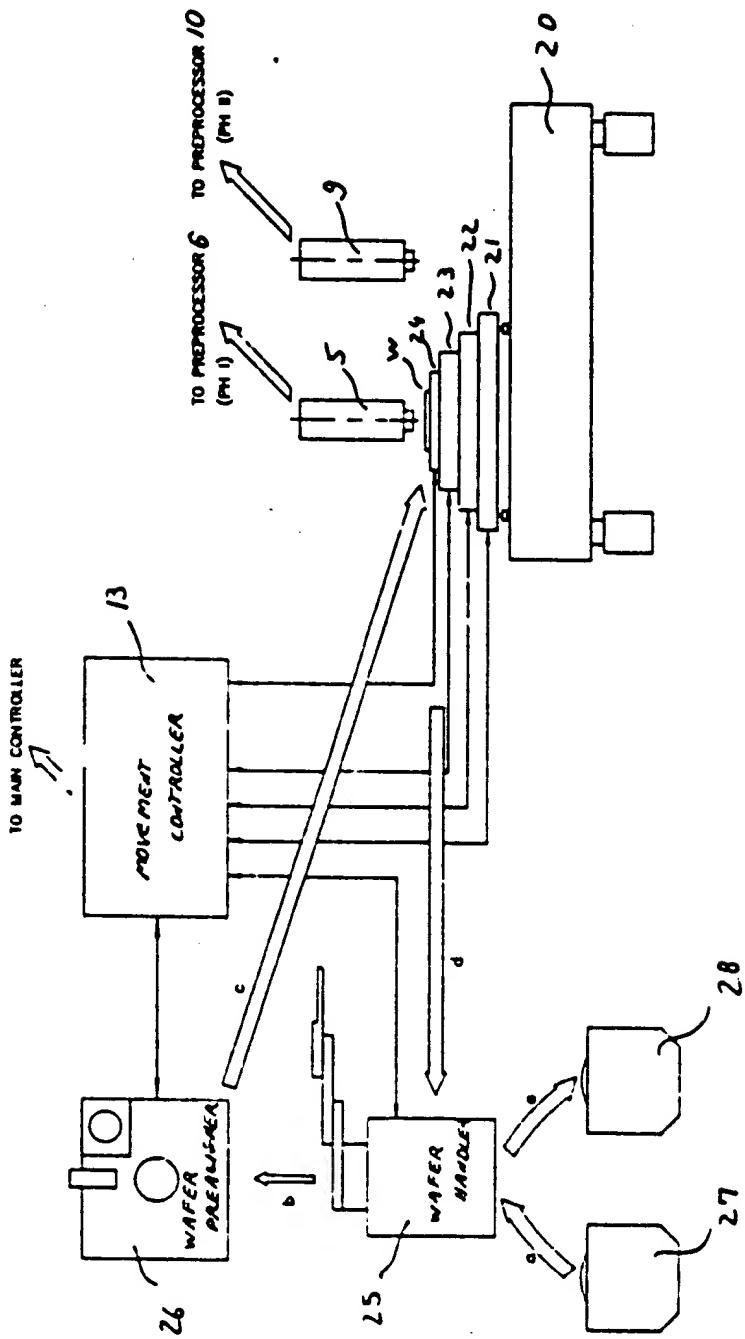
11/790871



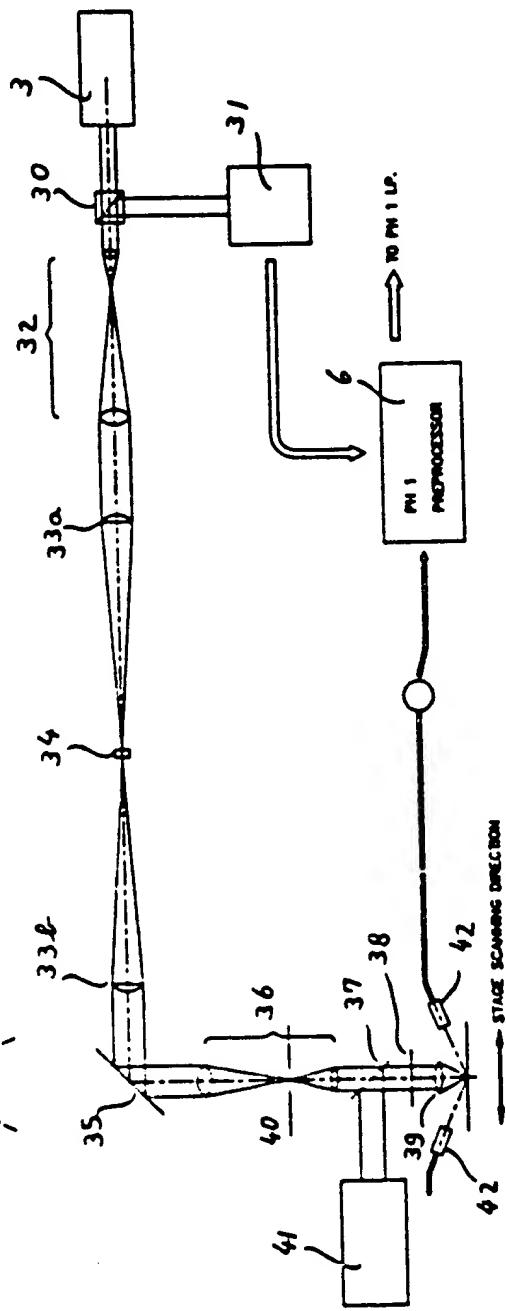
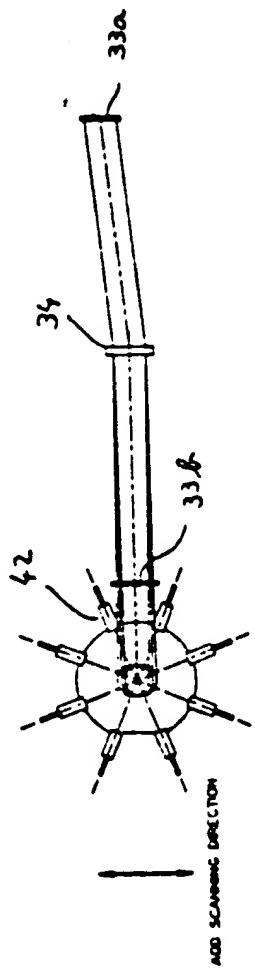
System Block Diagram

Fig. 2

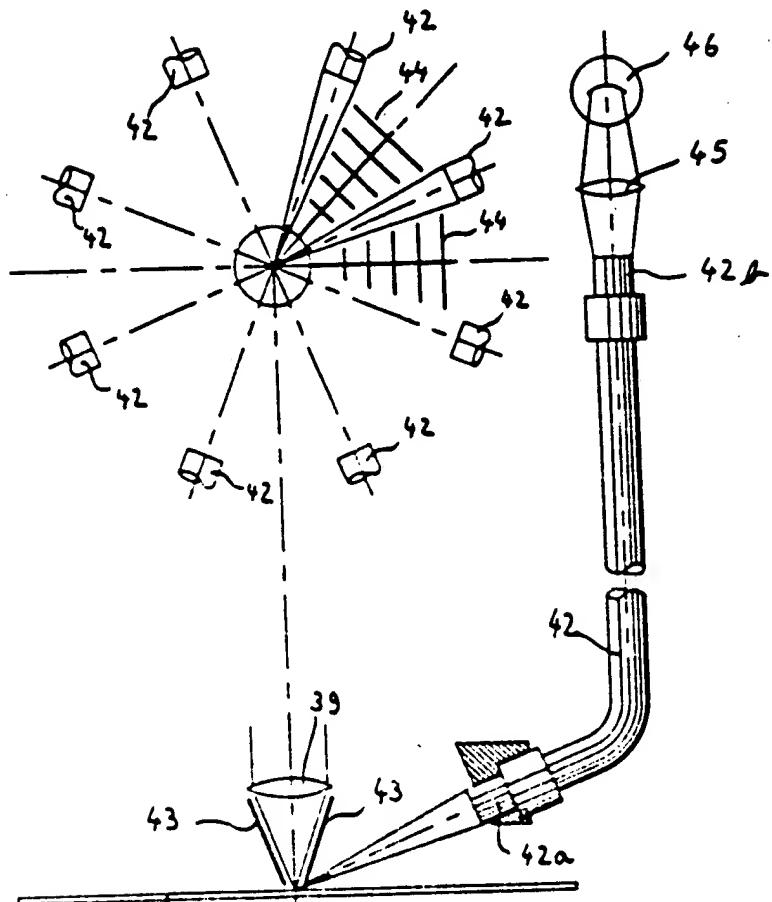
11/790871

Fig 3

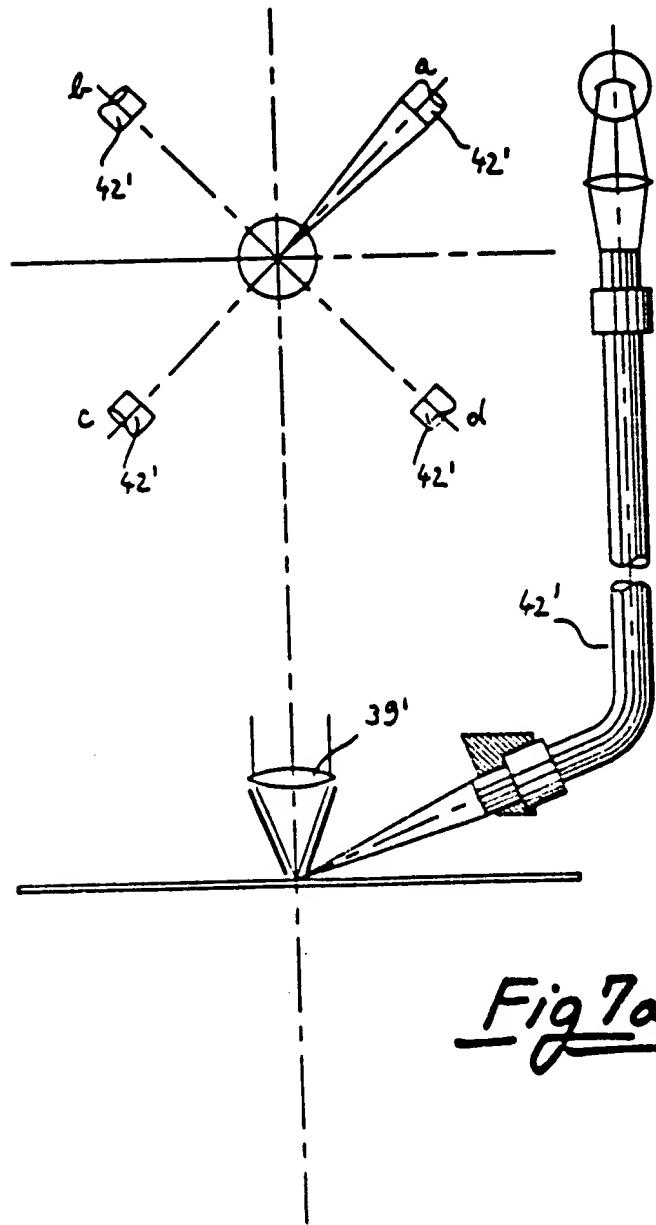
11/790871

Fig 5Fig. 4

11/790871

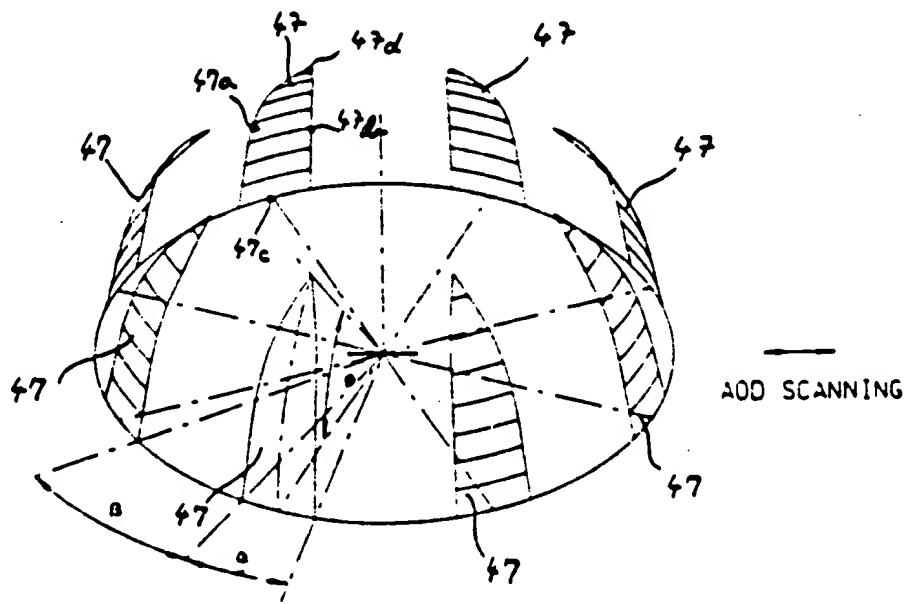
Fig 6Fig. 7

11/790871

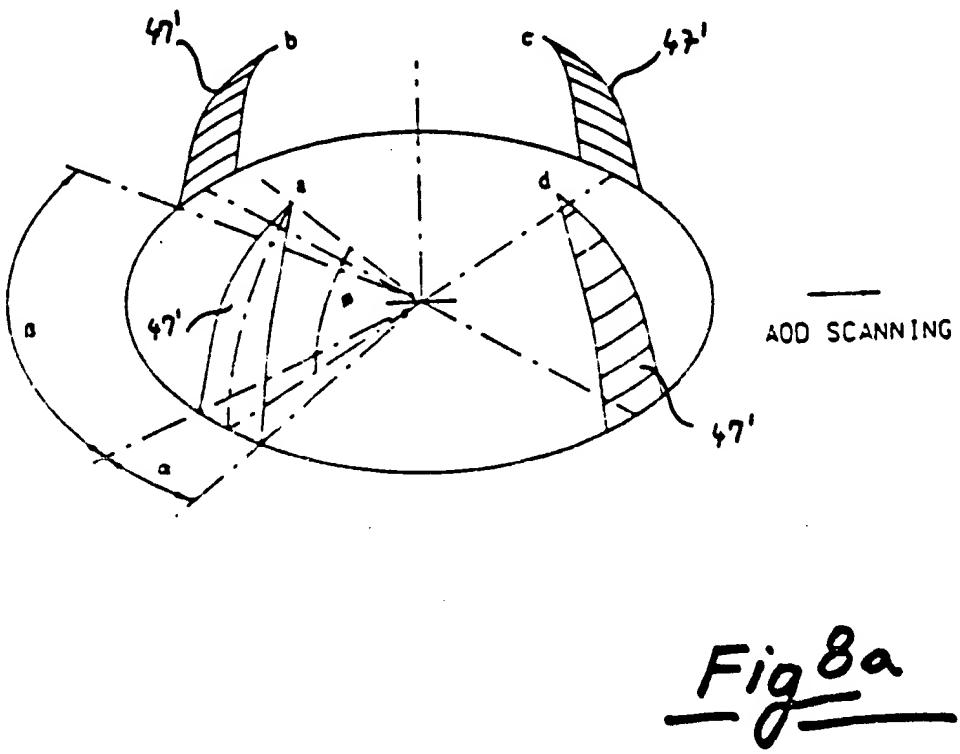
Fig 6aFig 7a

11/790871

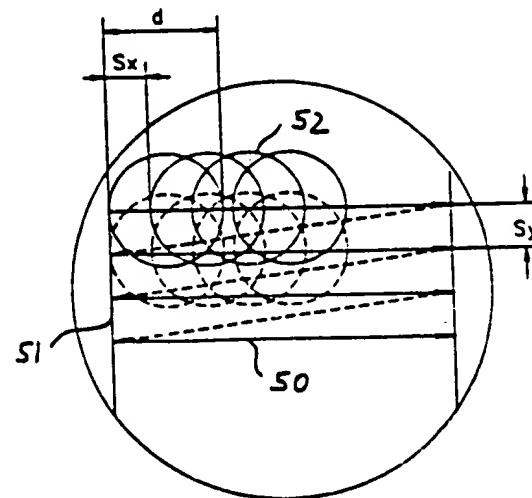
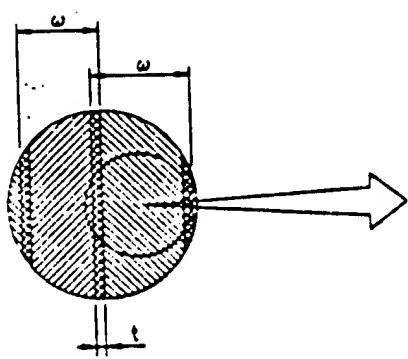
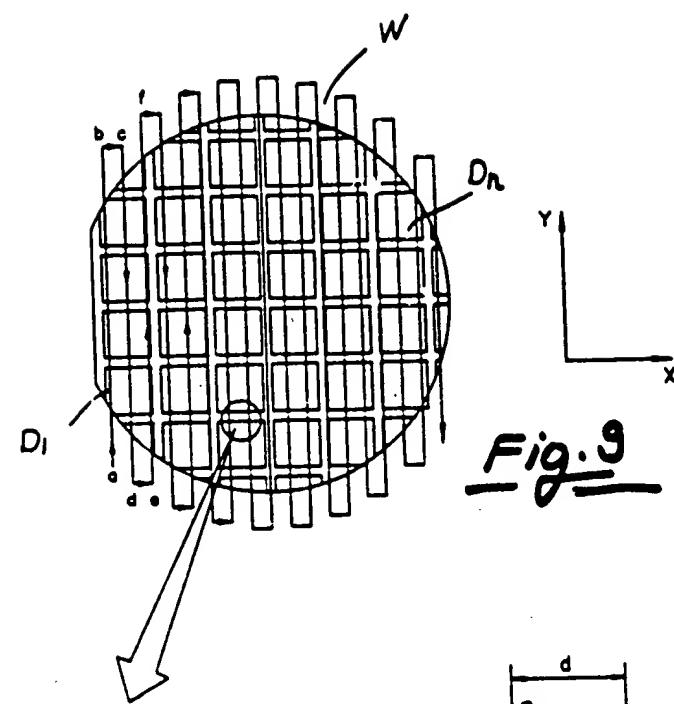
Fig. 8



90871



11/790871



10/91

11/790871

Phase 1 I.P. Overall Functional Block Diagram

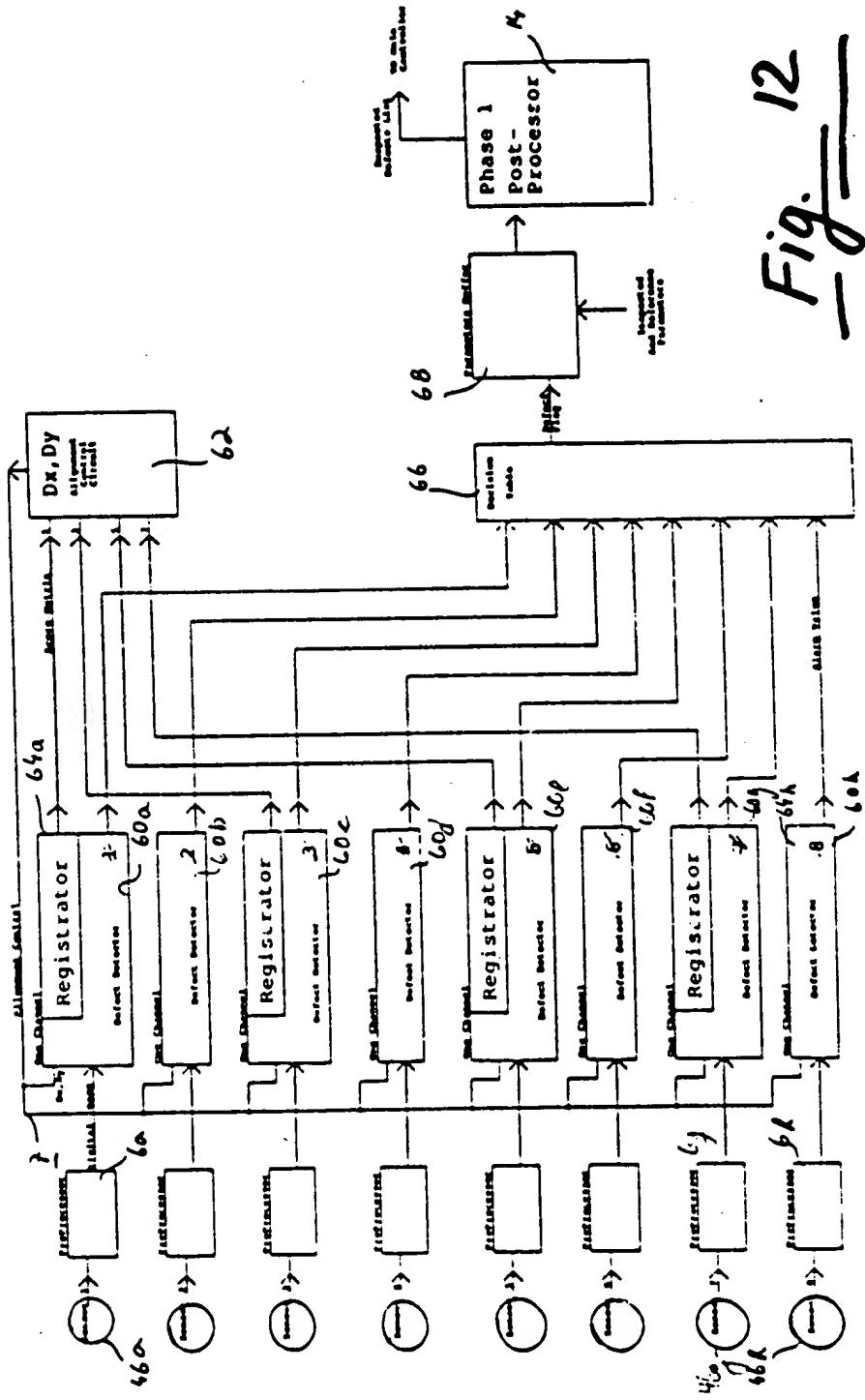


Fig. 12

11/41

11/790871

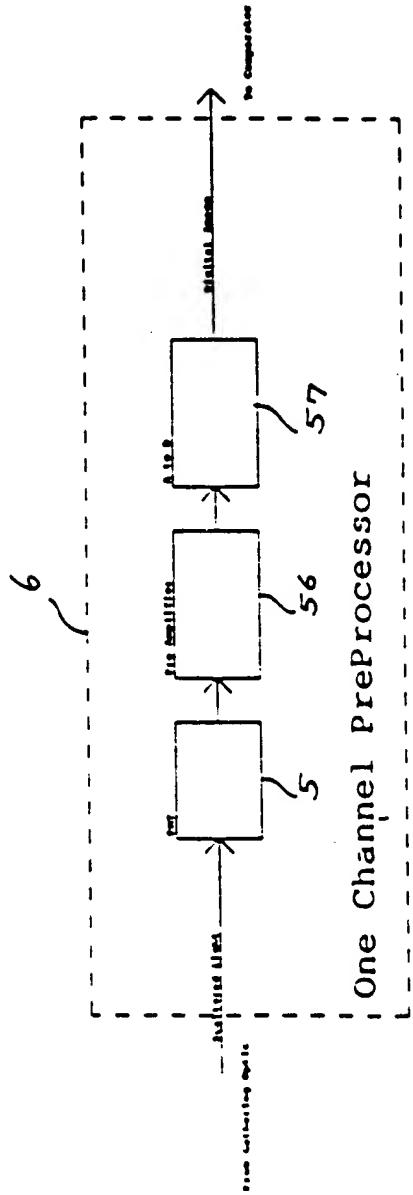
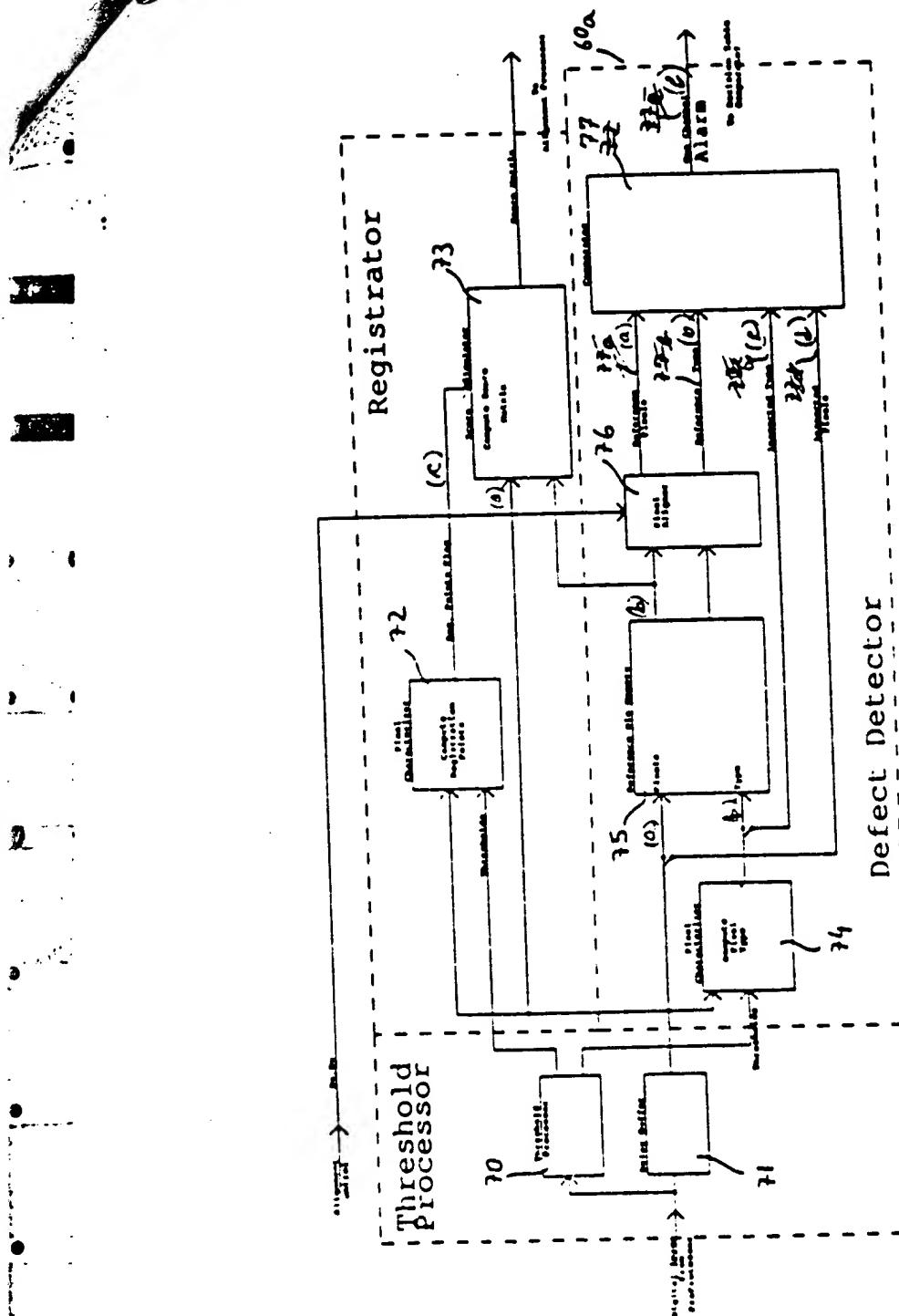


Fig. 13

12/41

11/790871

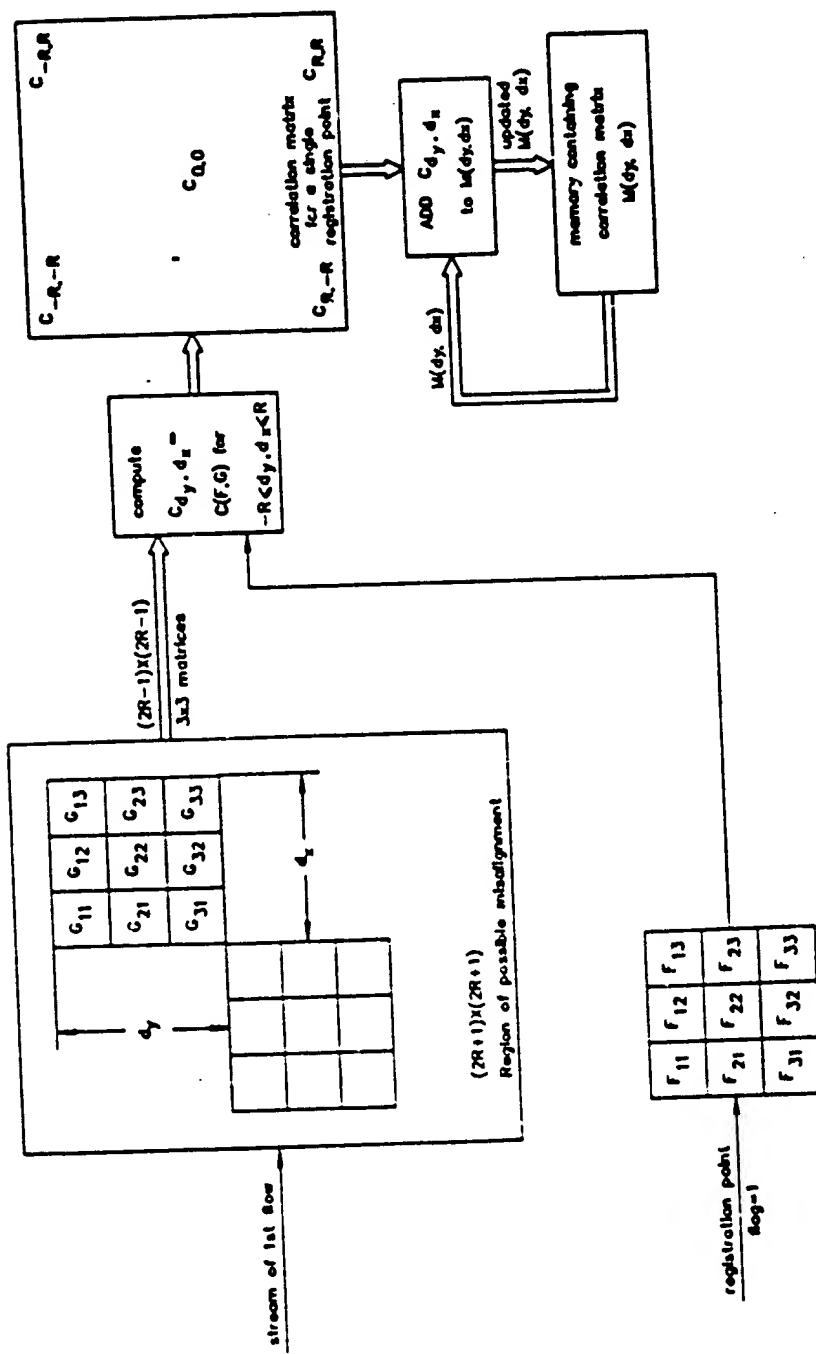


One Channel I.P. Block Diagram

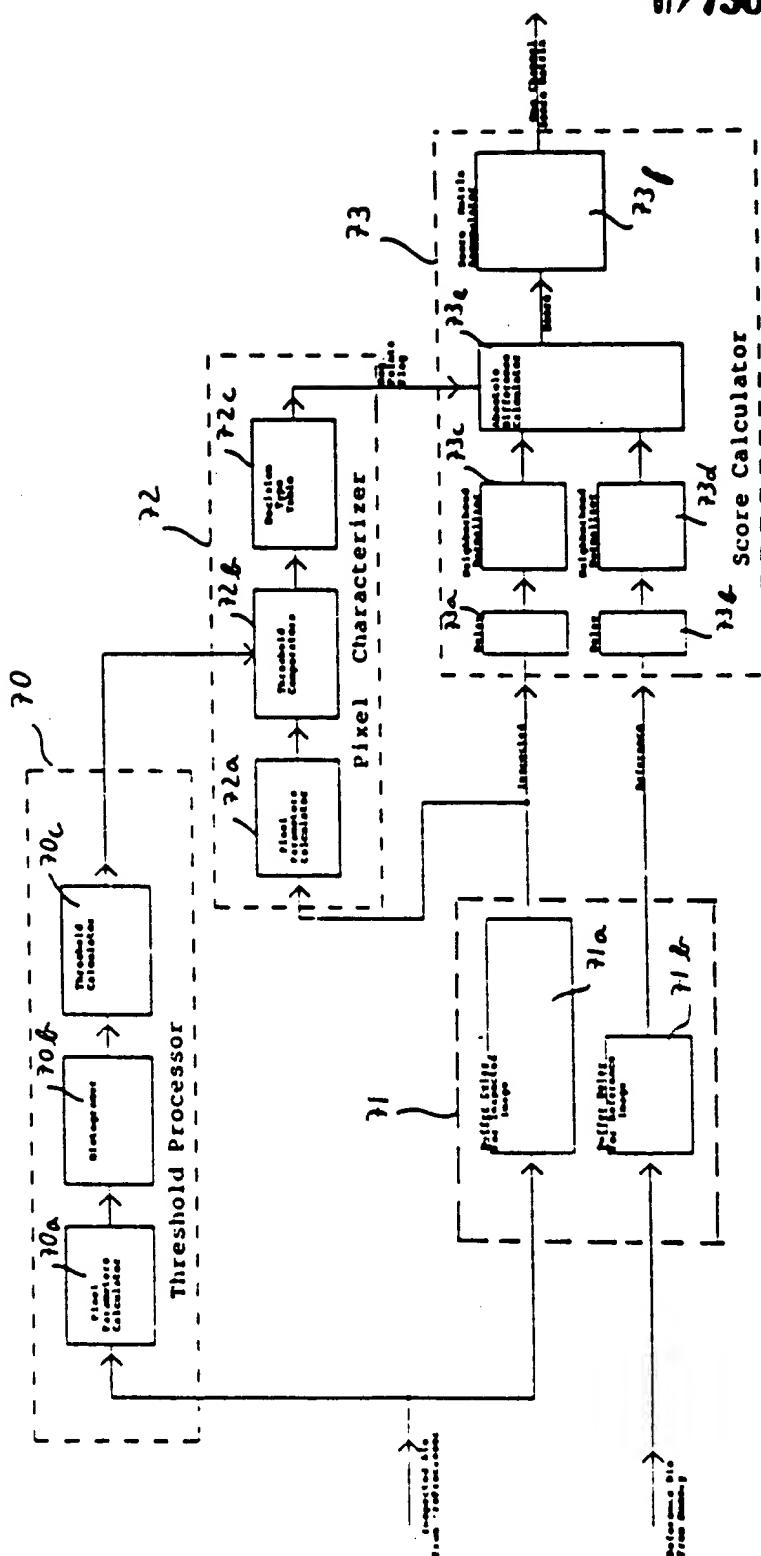
Fig. 14

11/790871

Fig. 14a

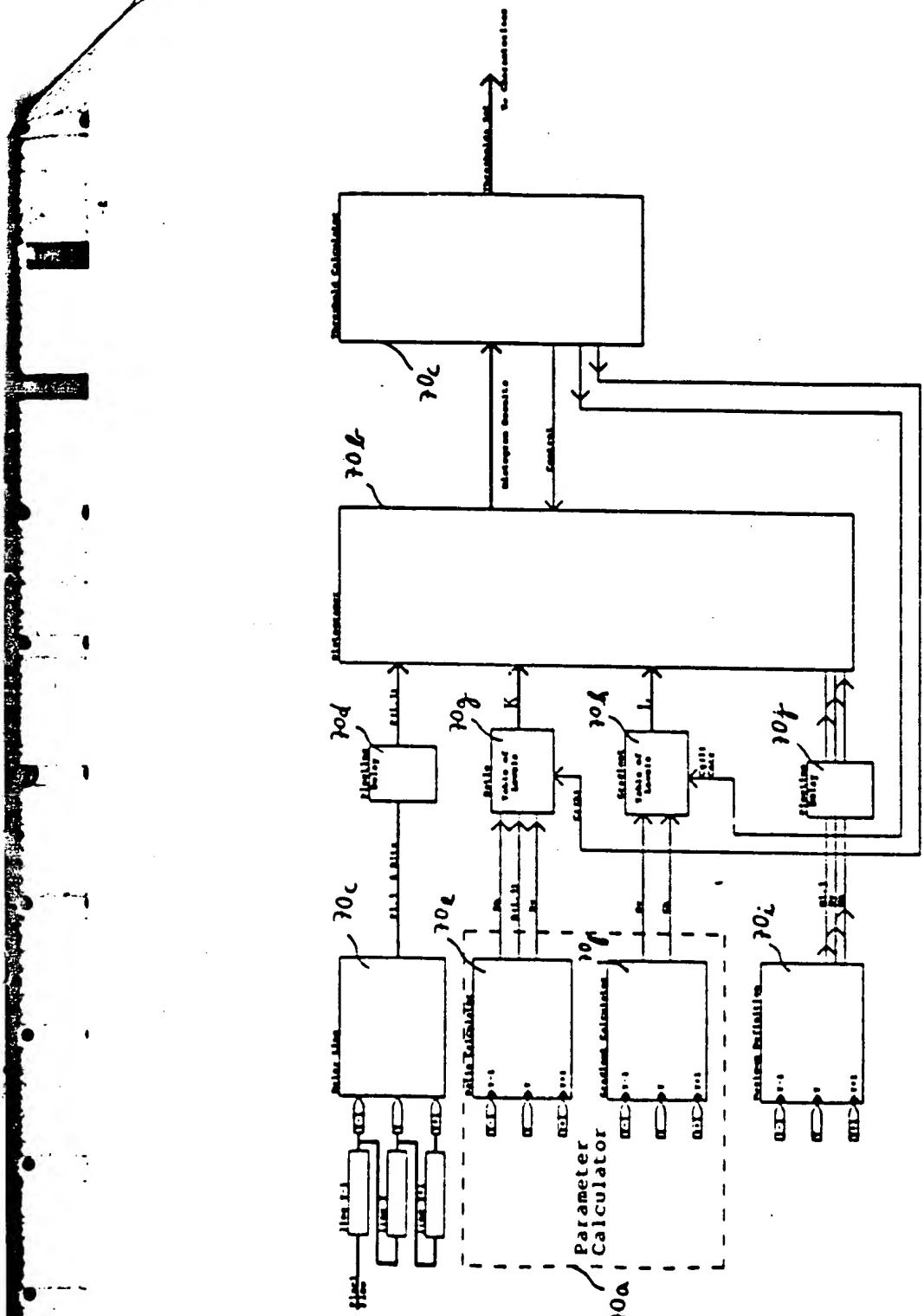


11/790871



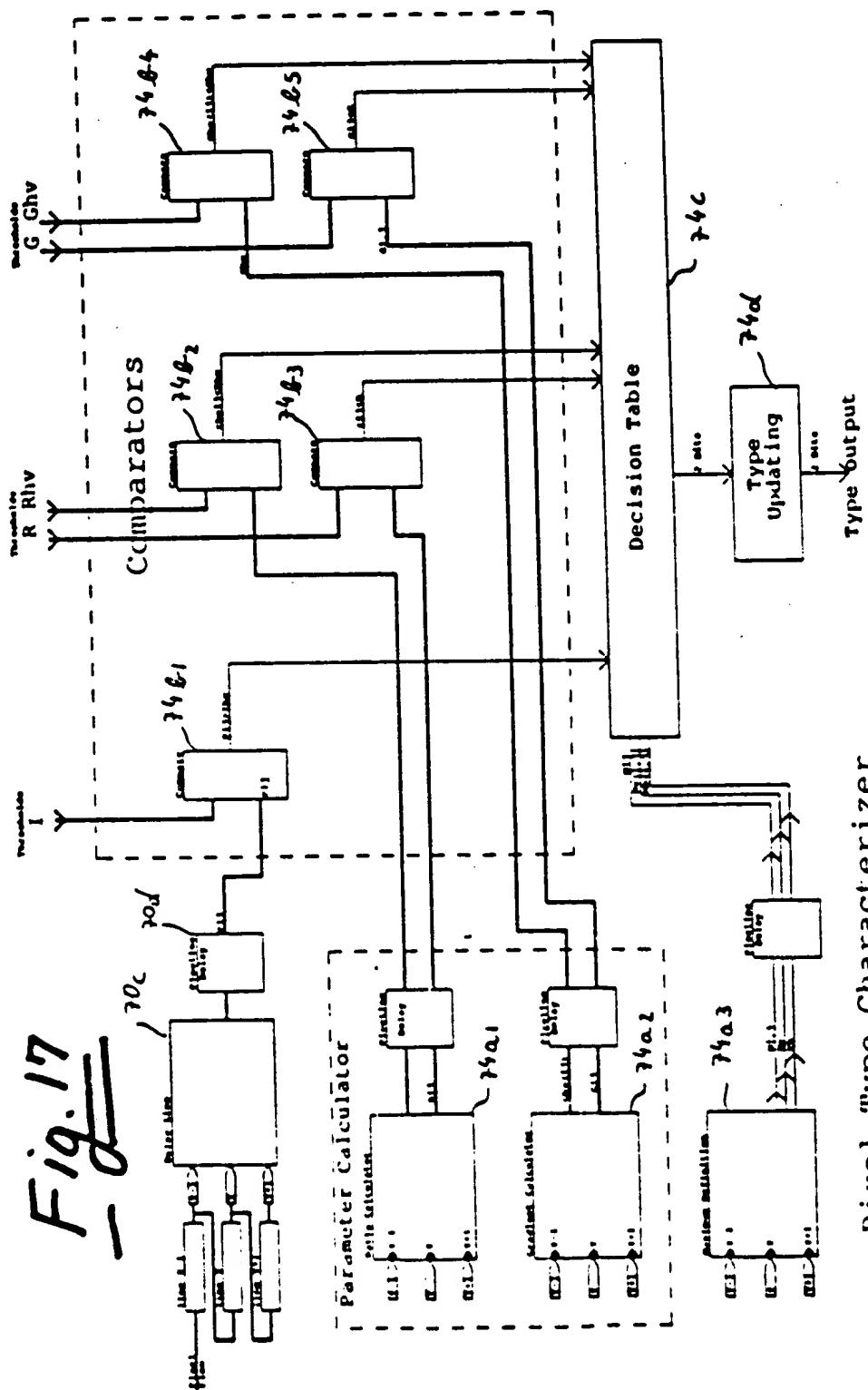
Registrator Block Diagram

Fig. 15

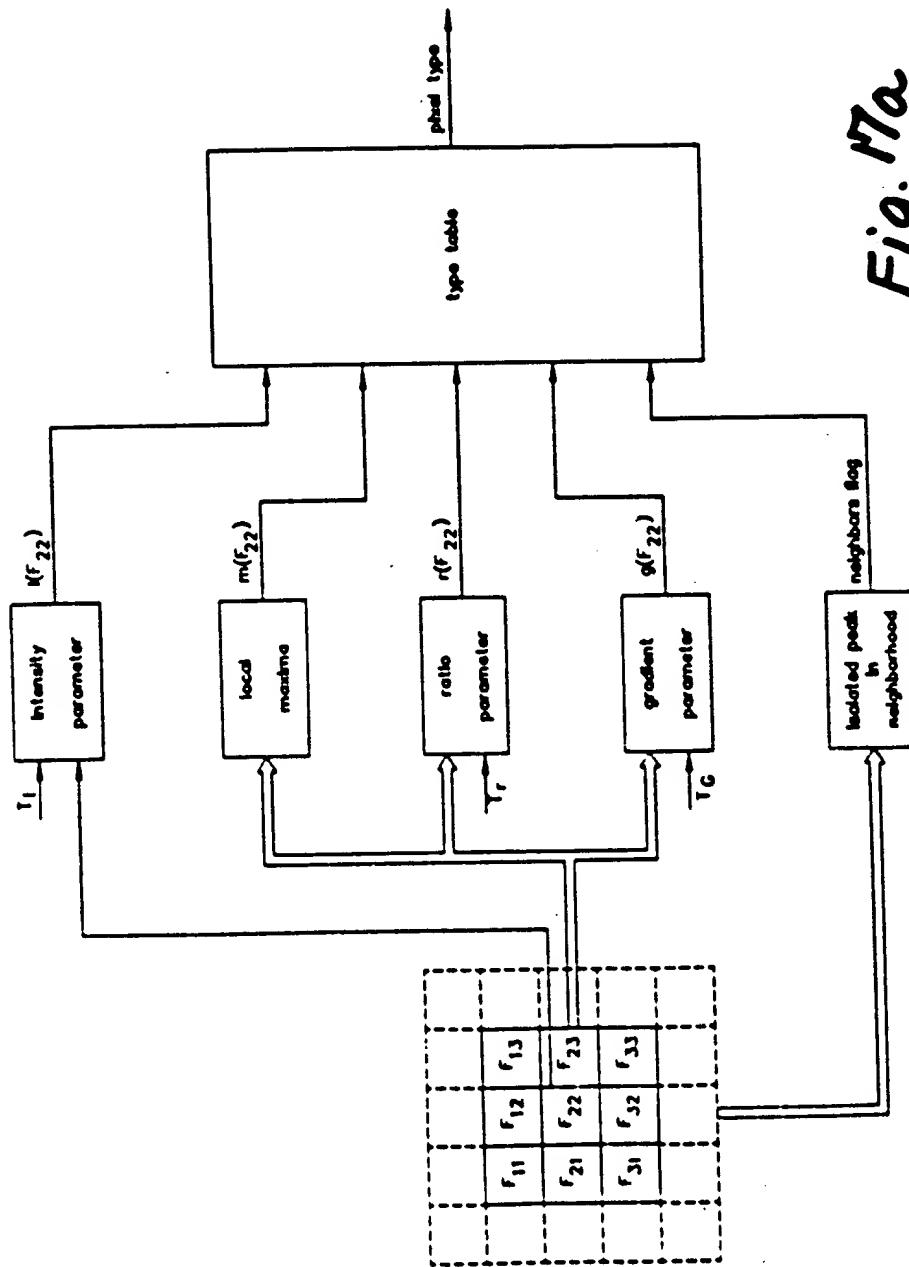


Threshold Processor Block Diagram

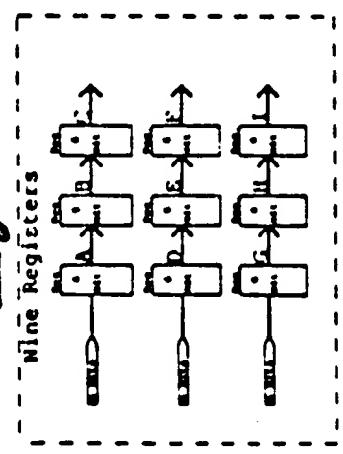
Fig. 16



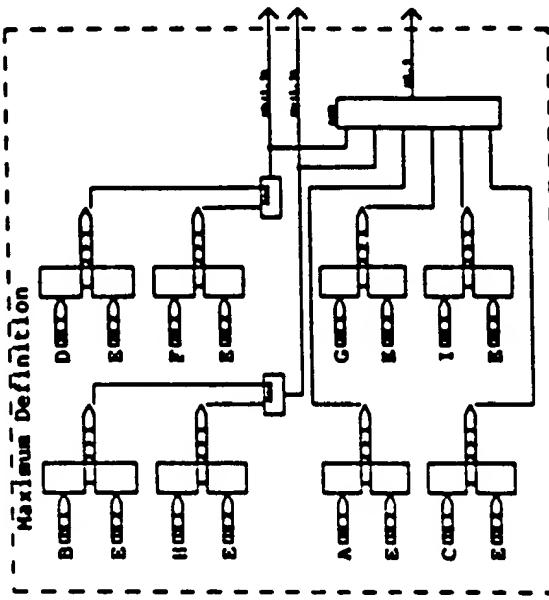
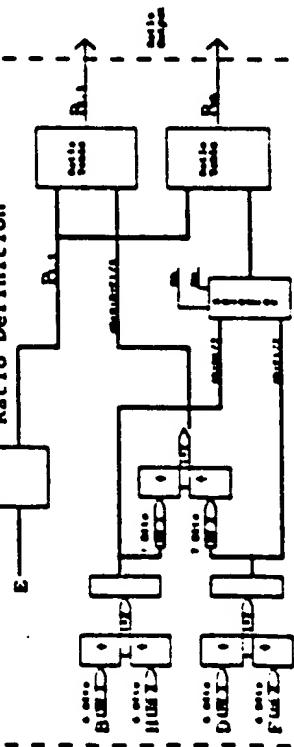
11/790871

Fig. 17a

11/790871

Fig. 2/α

Maximum Definition

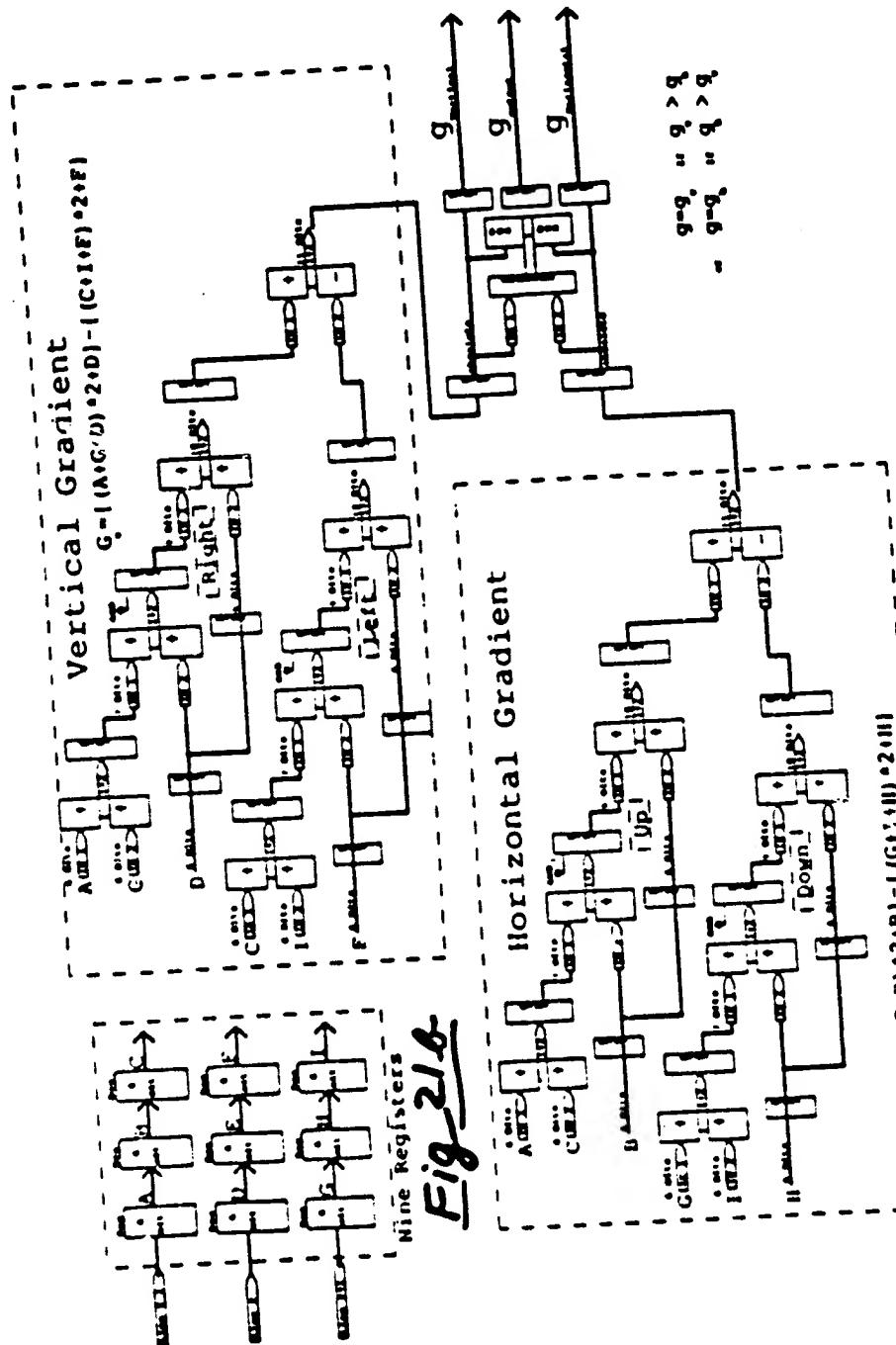
Fig. 20Fig. 18

Ratio And Maximum Definition

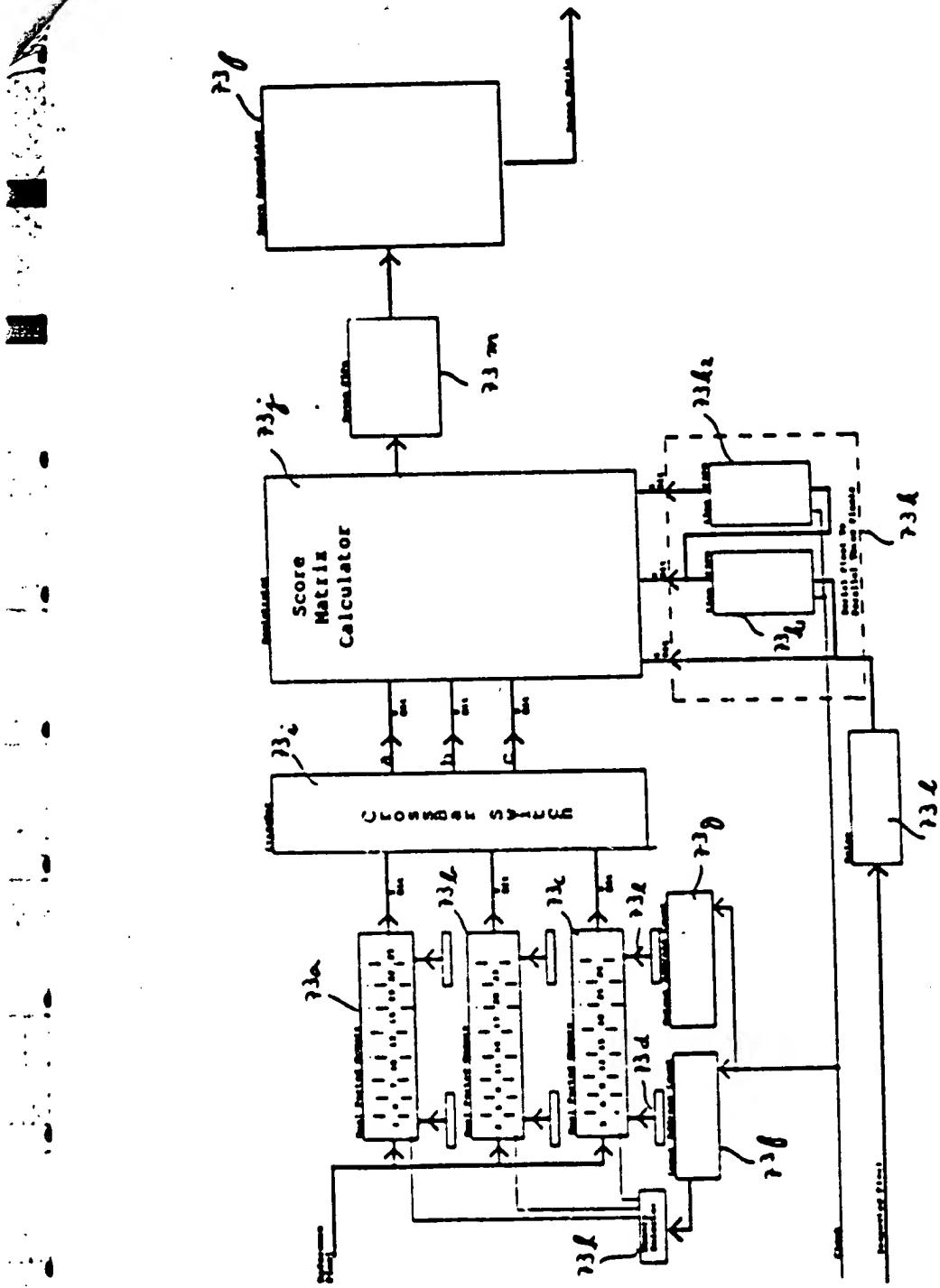
26 Oct 1954 9600

19/41

11/790871



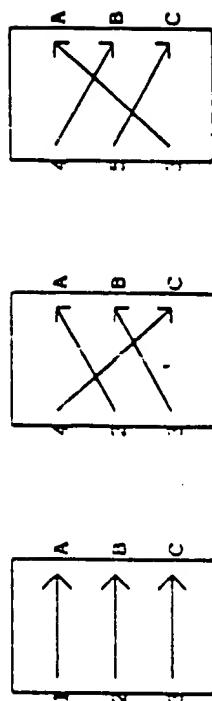
11/790871



Registration Score Matrix Calculator
Fig. 22

21/41

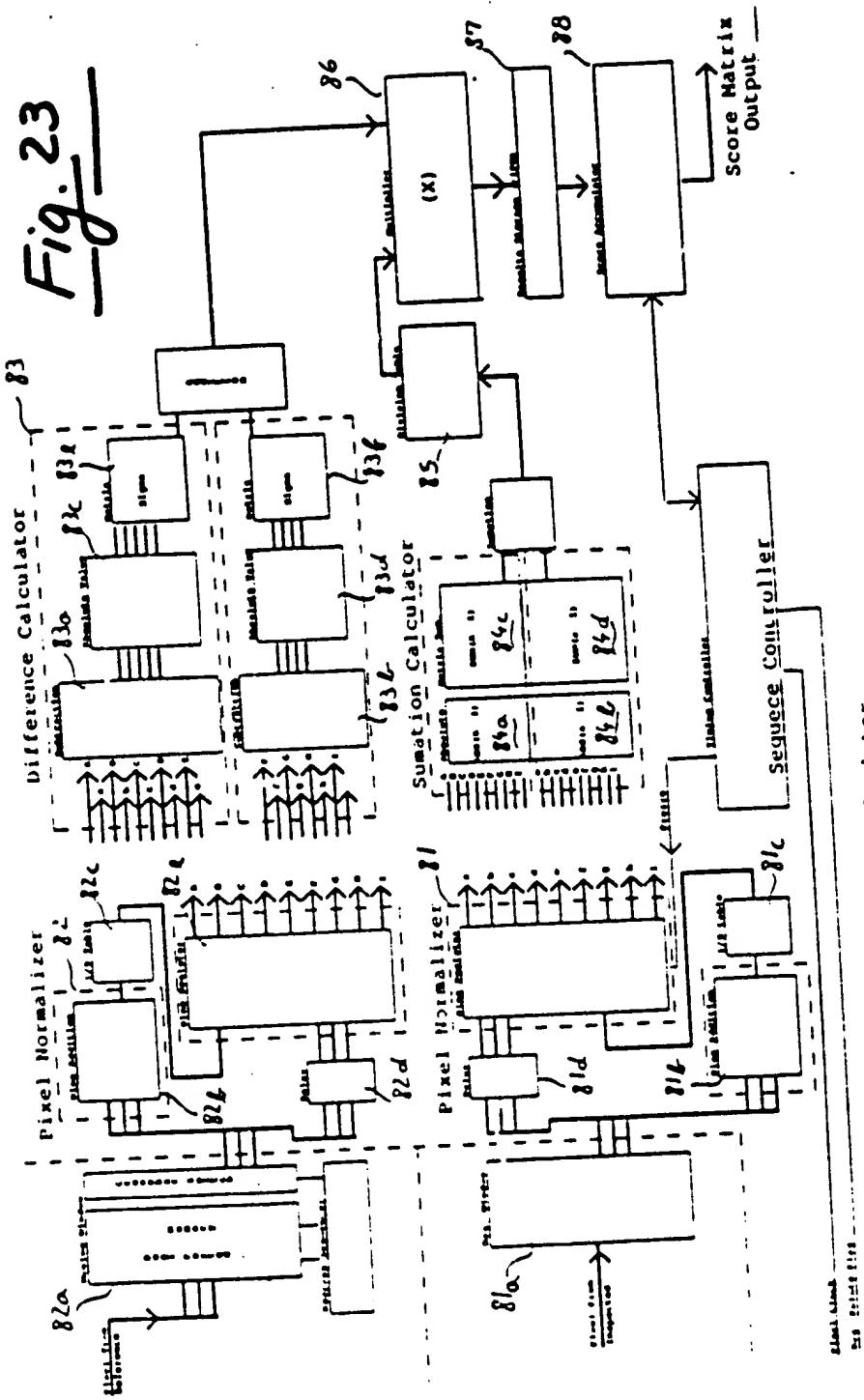
11/790871



CrossBar Switch Combination

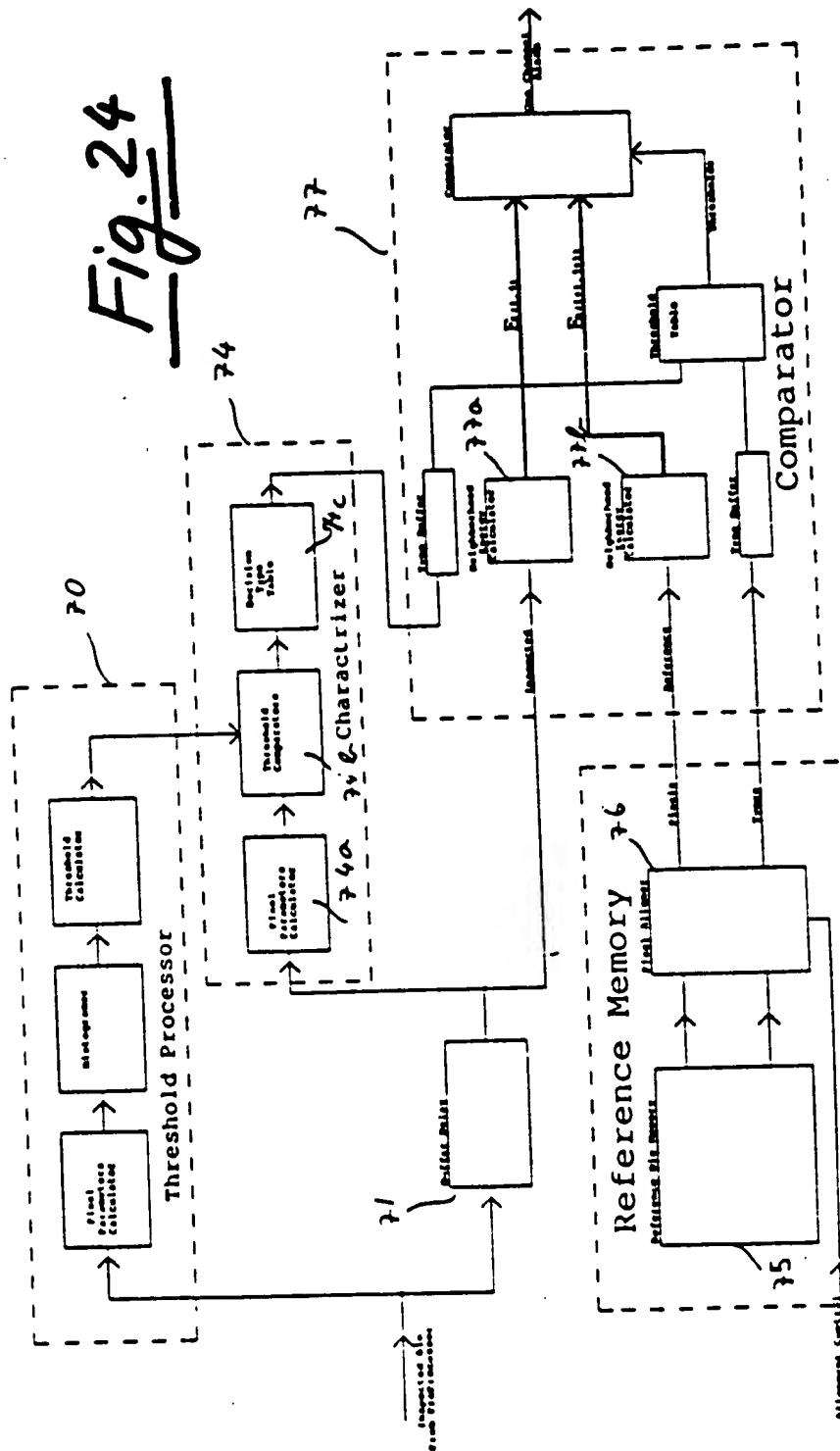
Fig. 22a

11/790871

Fig. 23

11/790871

Fig. 24

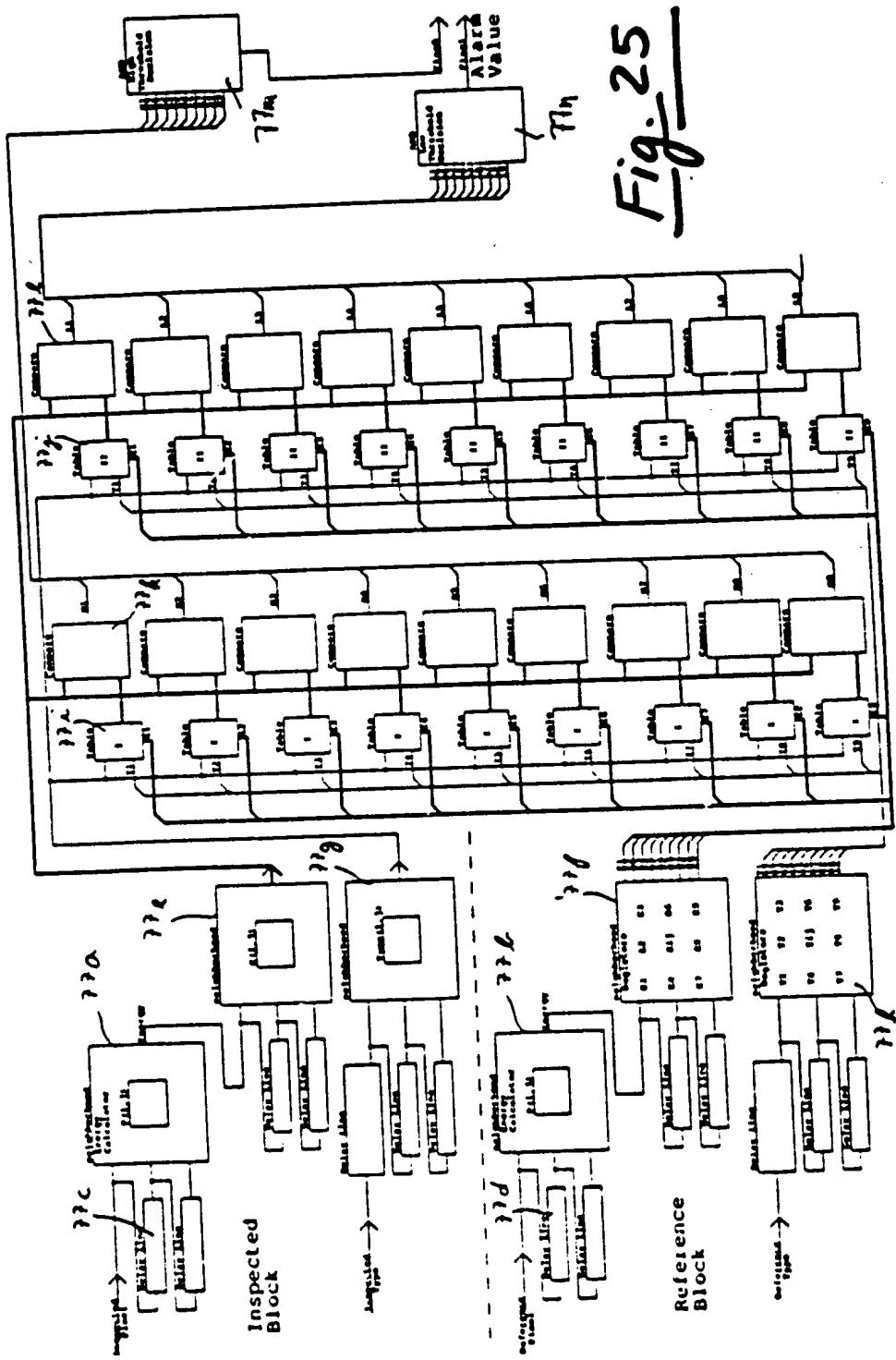


Defect Detector Block Diagram

24/41

11/790871

Fig. 25



11/790871

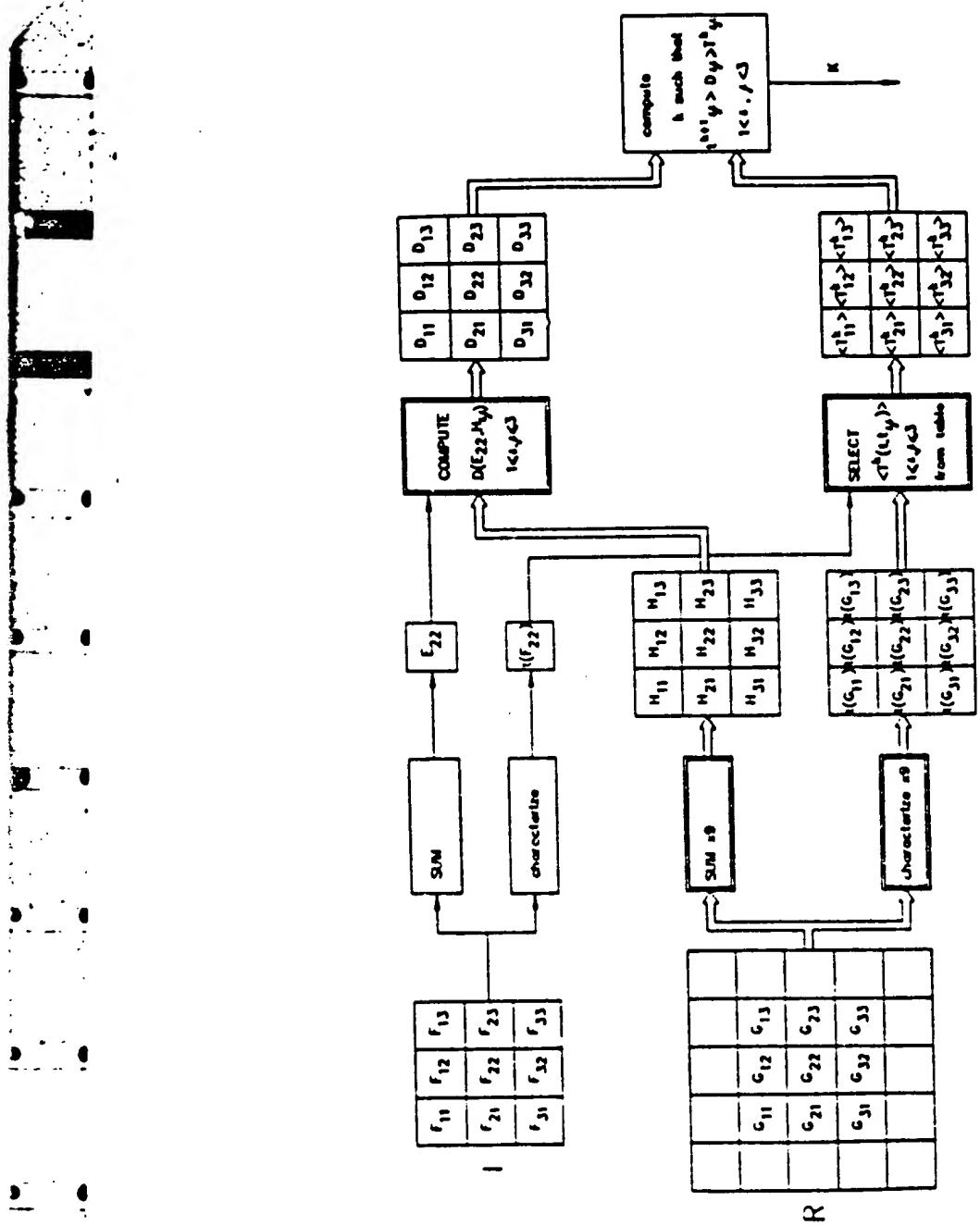
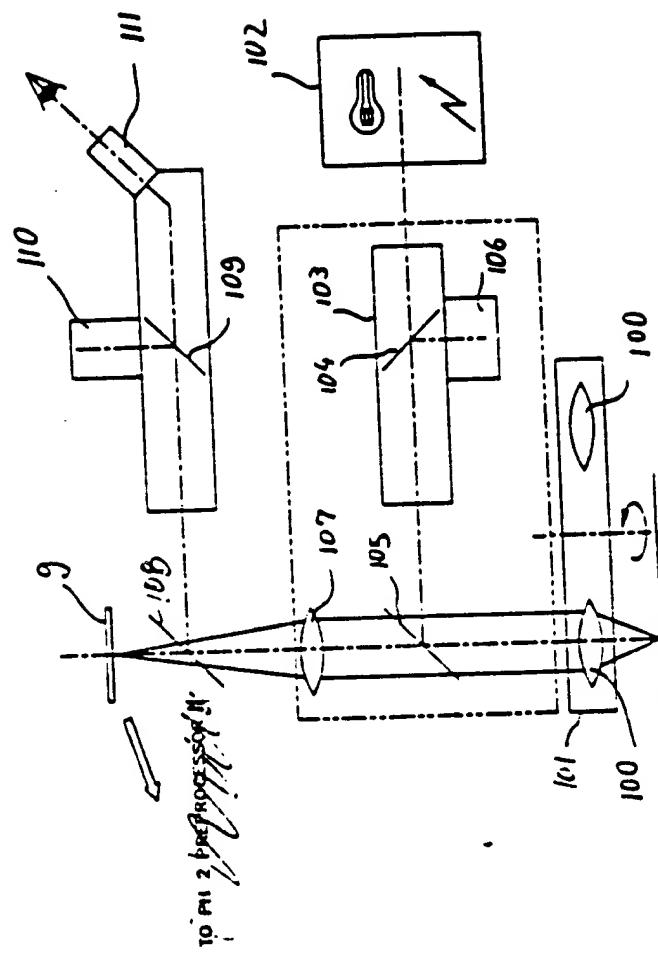


Fig. 25a

11/790871

Fig. 26

23/41

11/790871

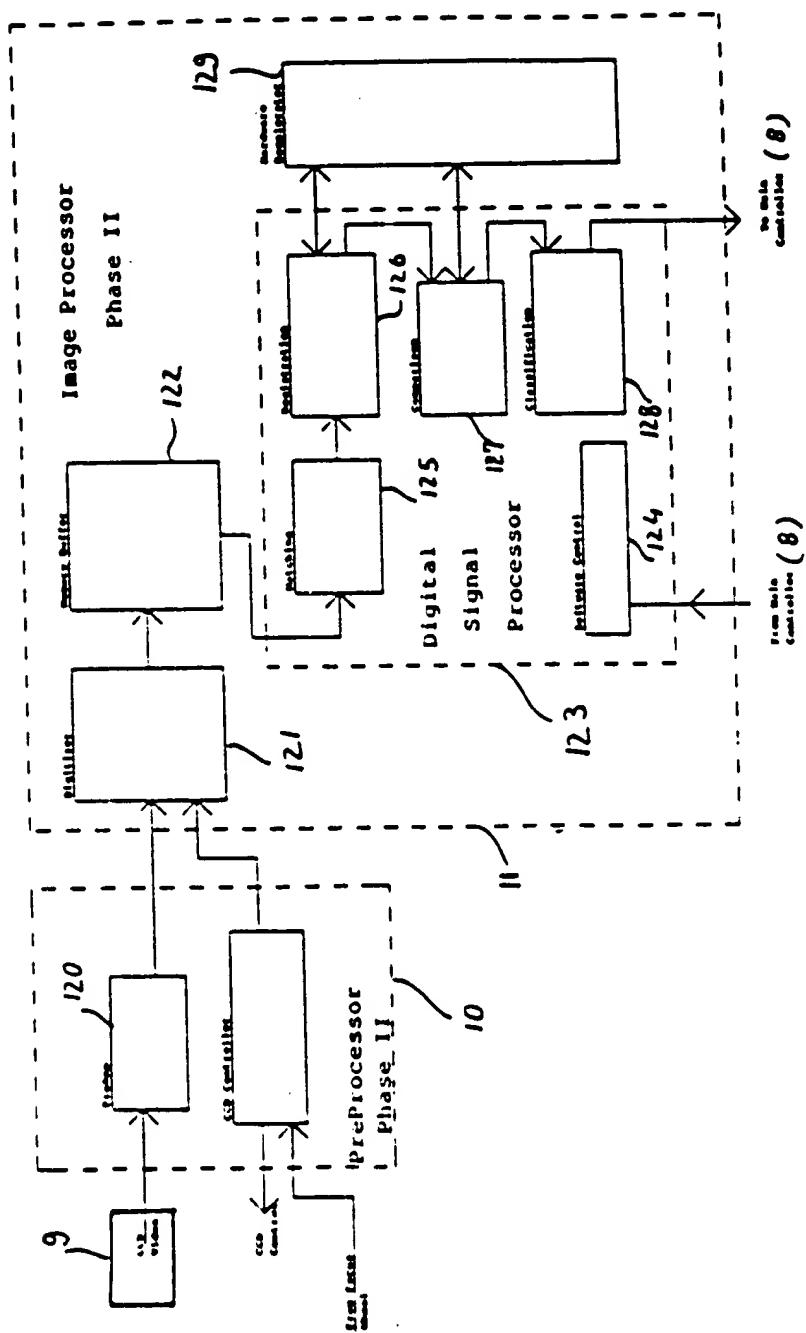


Fig. 27

11/790871 38/41

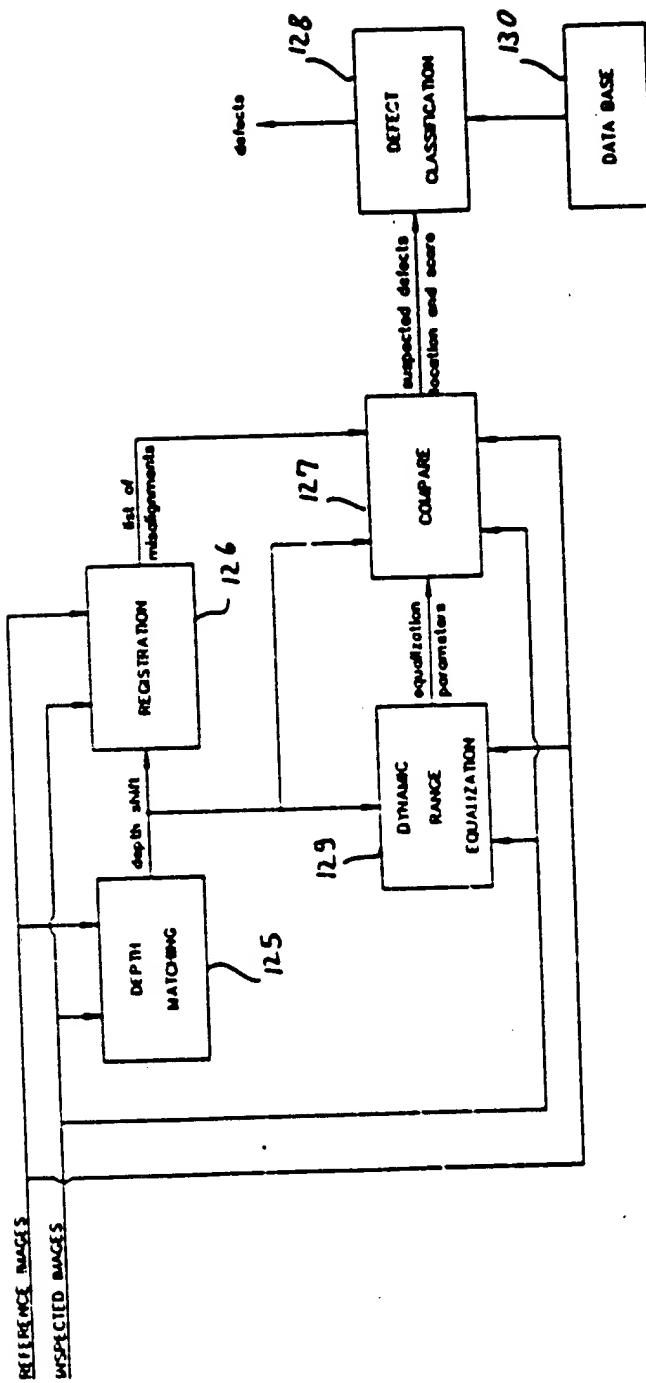
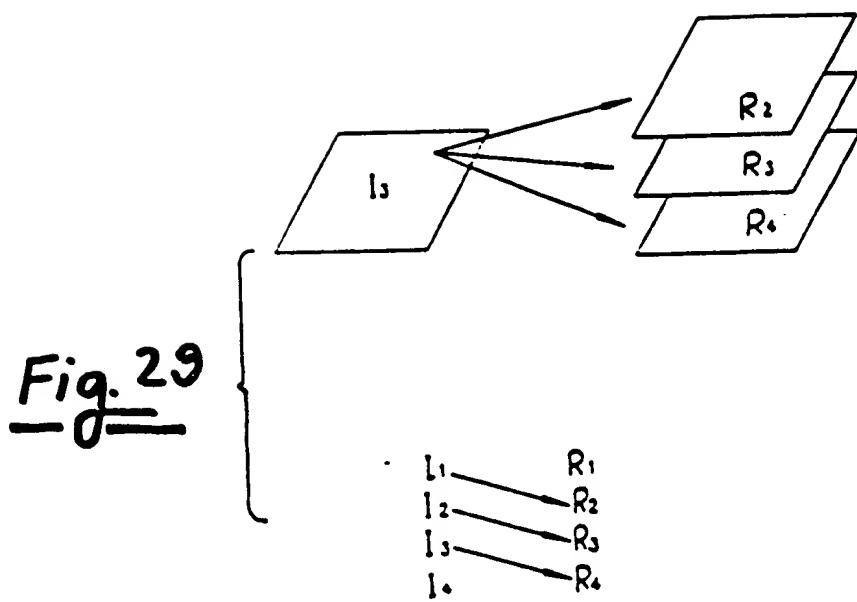


Fig. 28

29/41

11/790871



30/41

11/790871

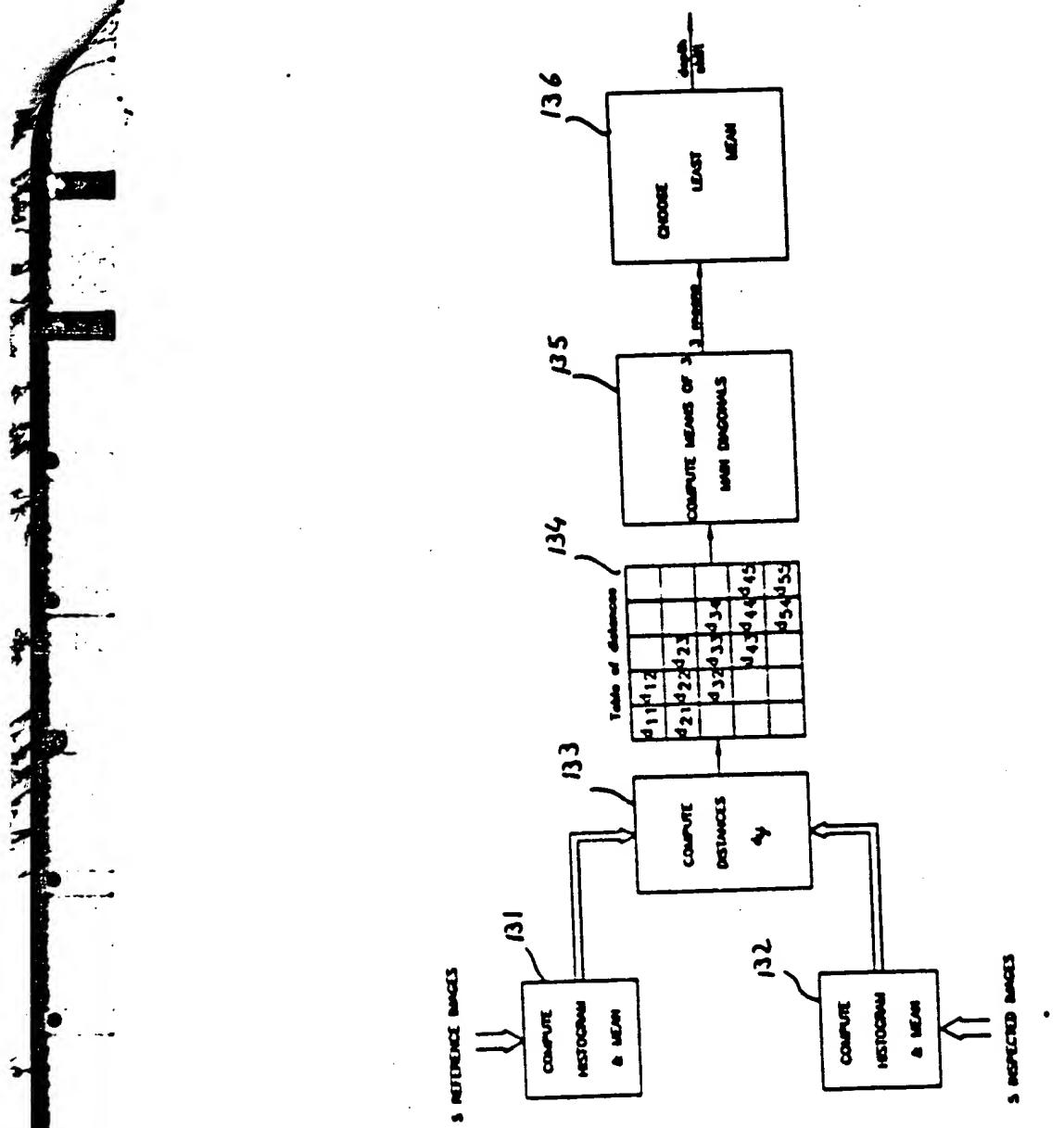


Fig. 30

31/41

11/790871

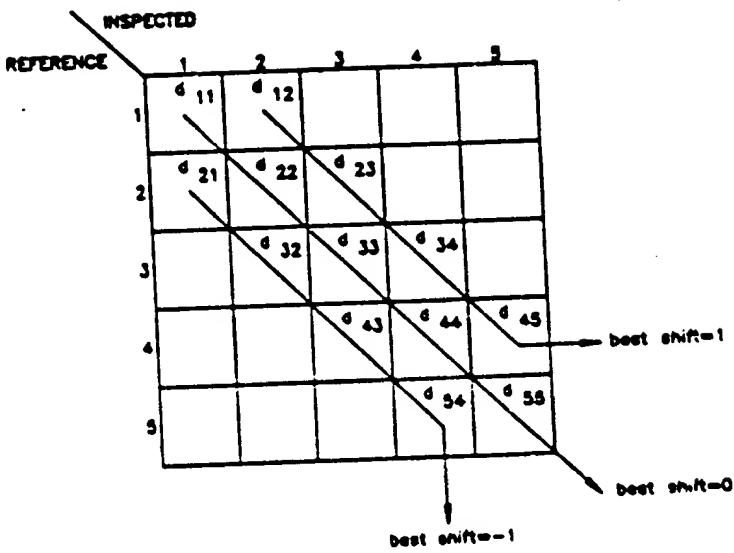


Fig. 31

11790871

32/41

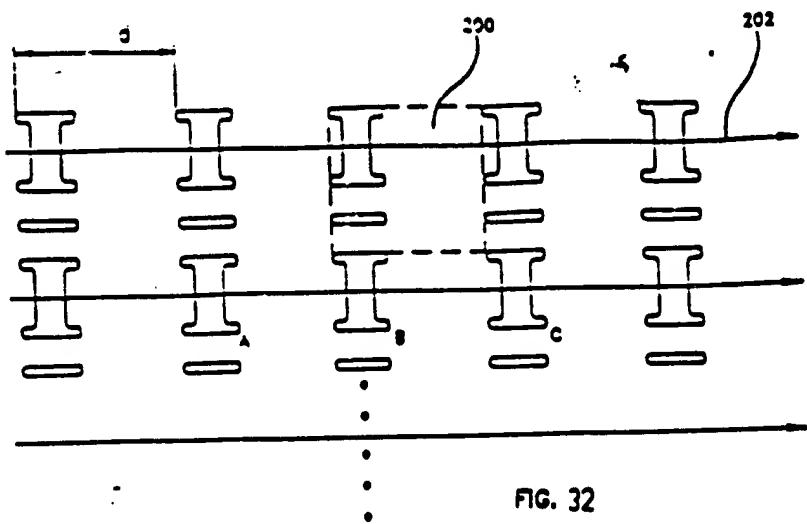


FIG. 32

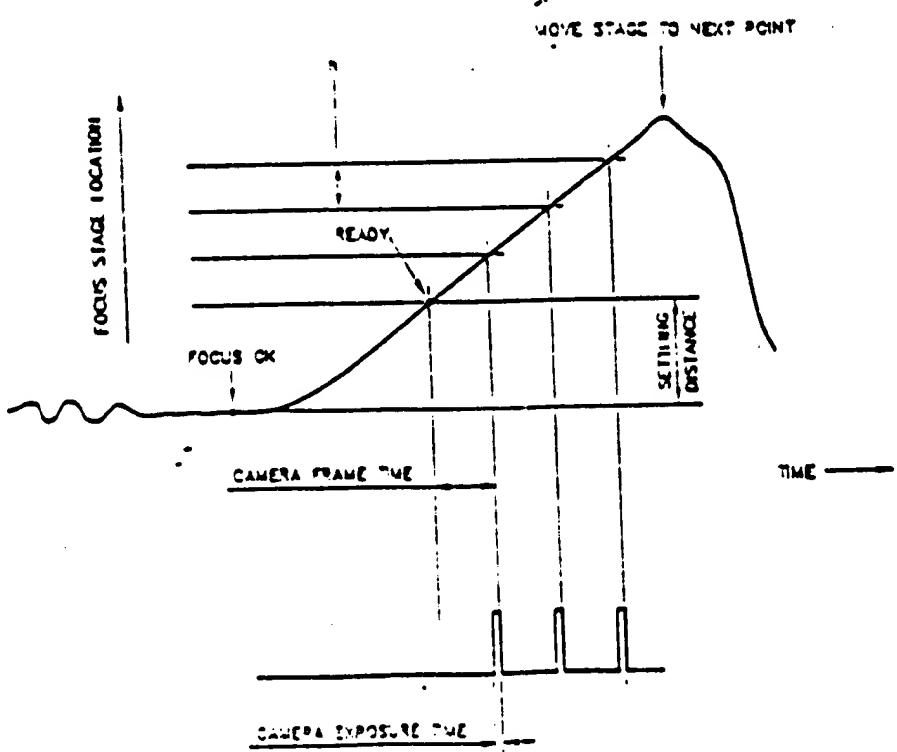


FIG. 37

11/790871

33/41

Phase 1 I.P. Overall Functional Block Diagram
a (Repetitive Pattern Inspection)

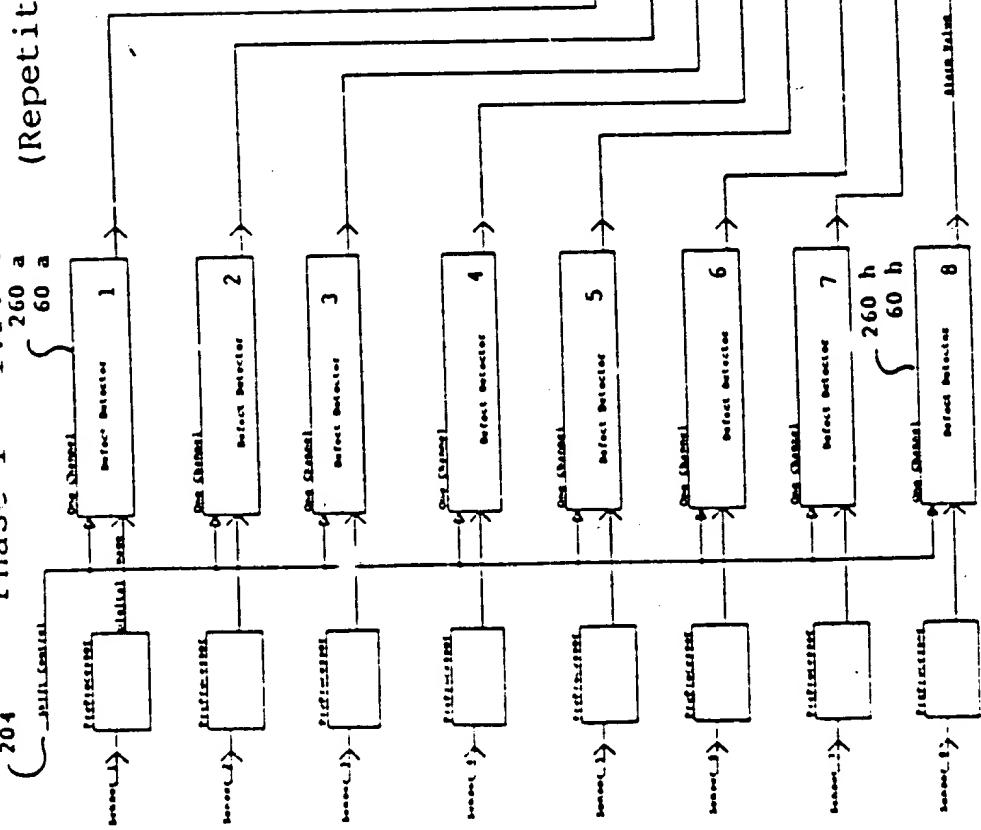
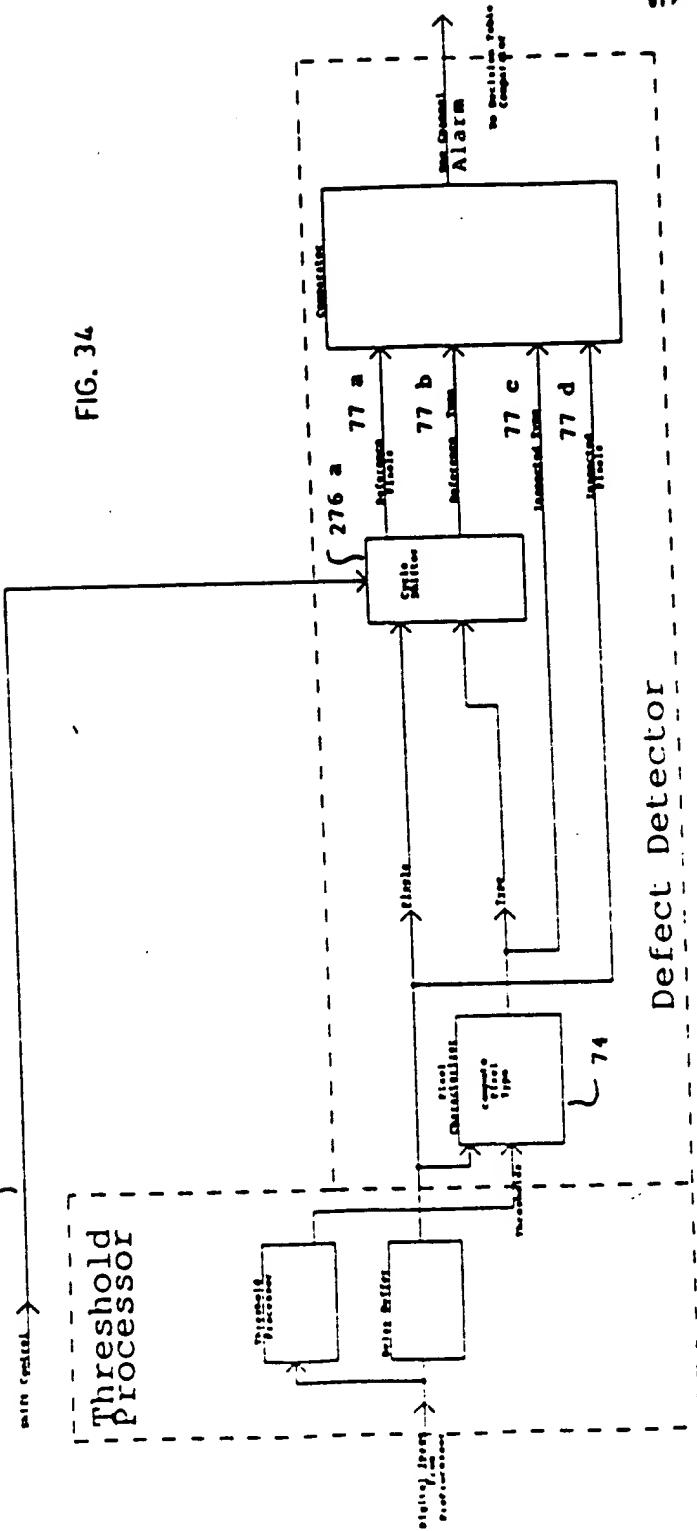


FIG. 33

204 11/790871 34/41

204

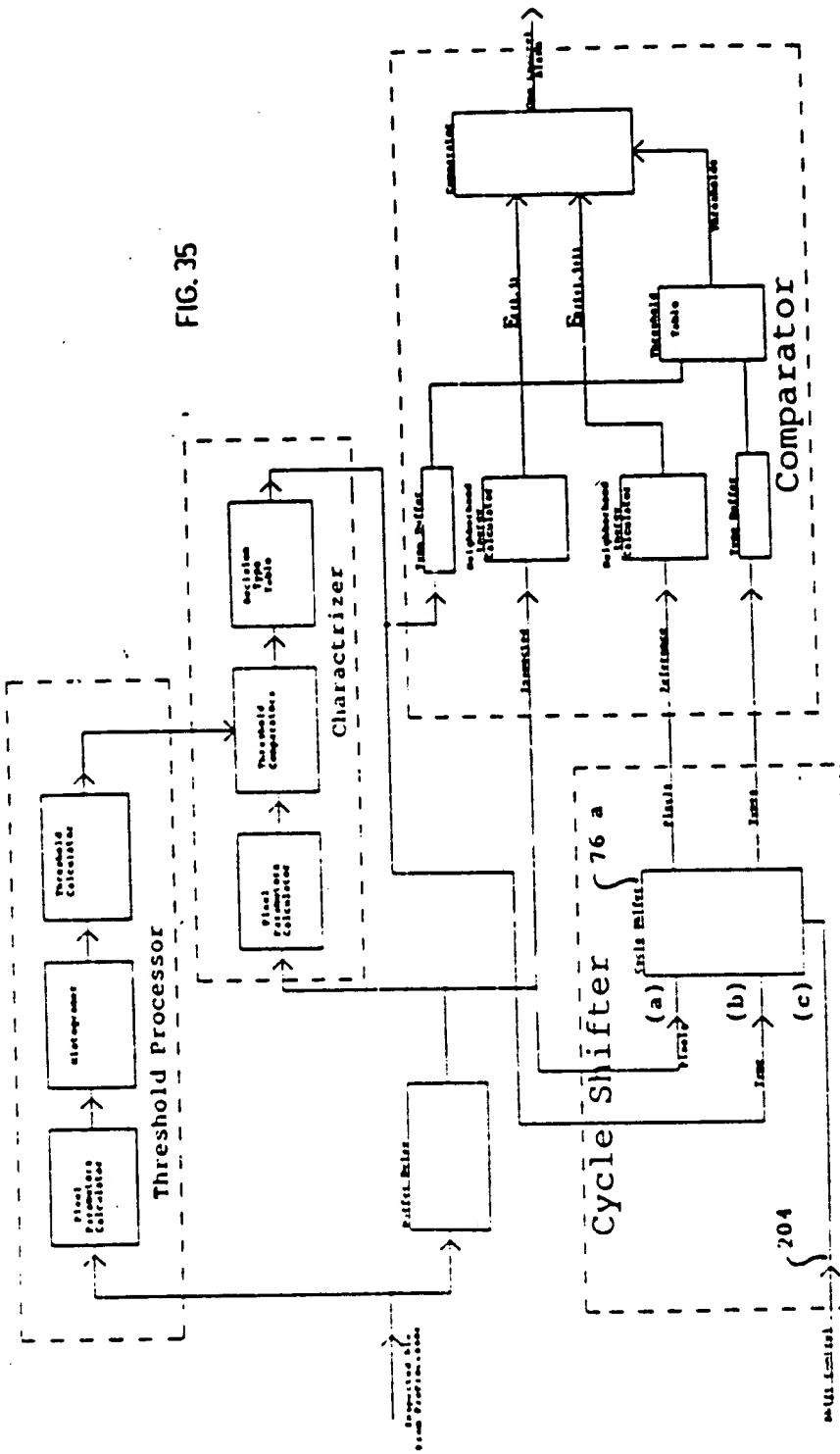
FIG. 34
Threshold Processor



One Channel T.P. Block Diagram
(Repetitive Pattern Inspection)

11/790871

FIG. 35



Defect Detector Block Diagram
(Repetitive Pattern Inspection)

117790871

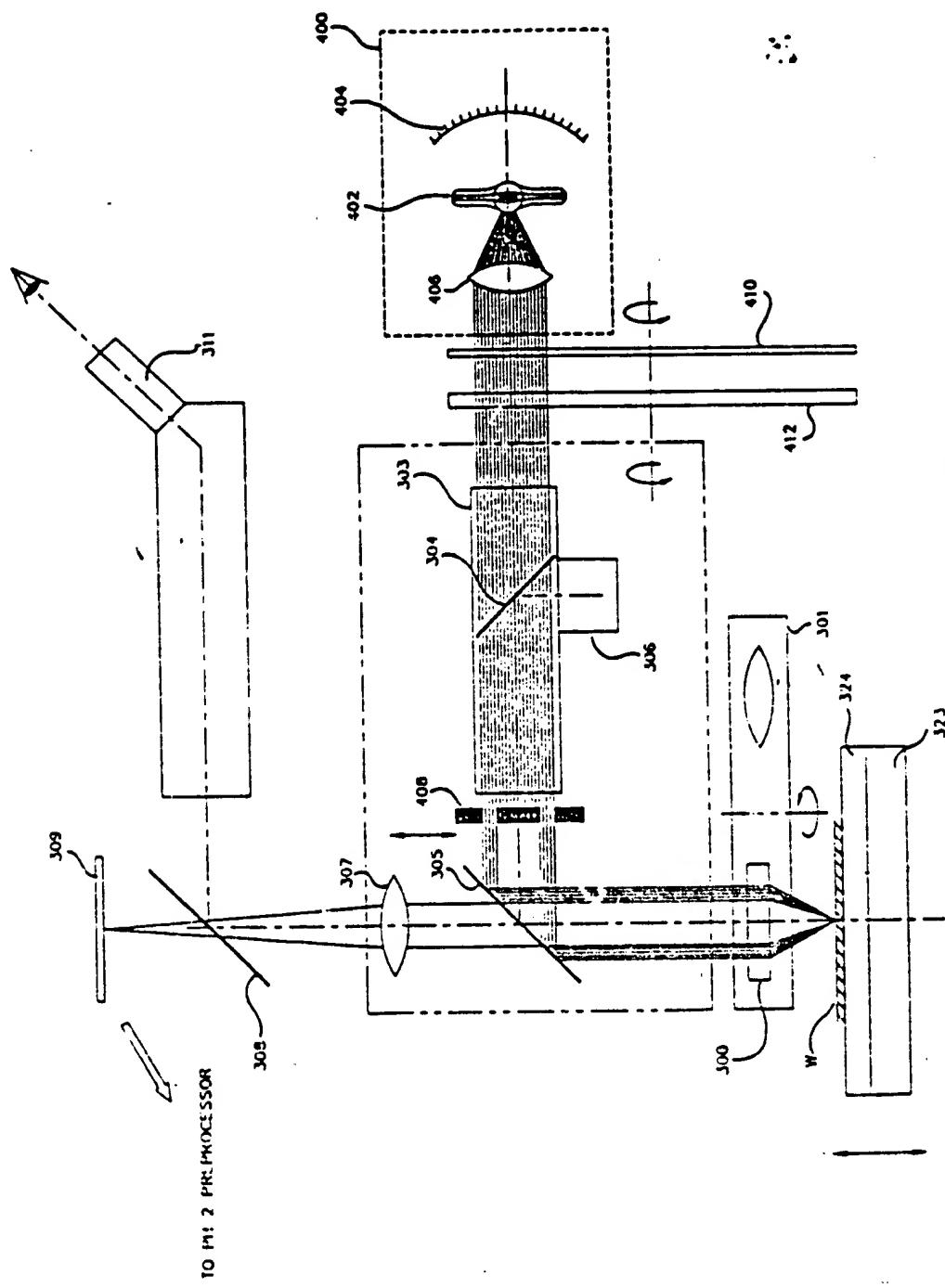


FIG. 36

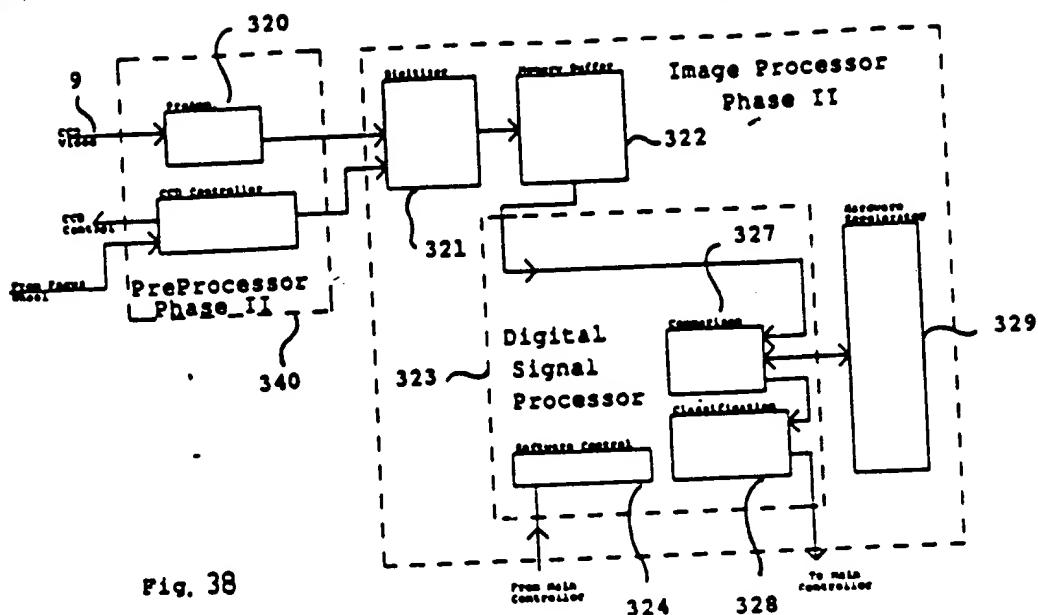


Fig. 38

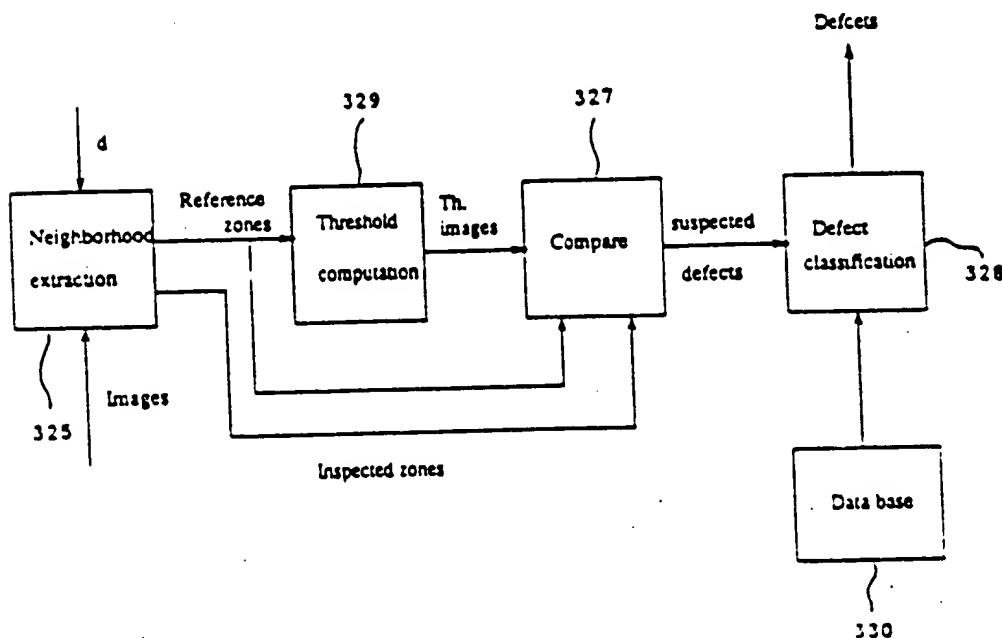


FIG. 37

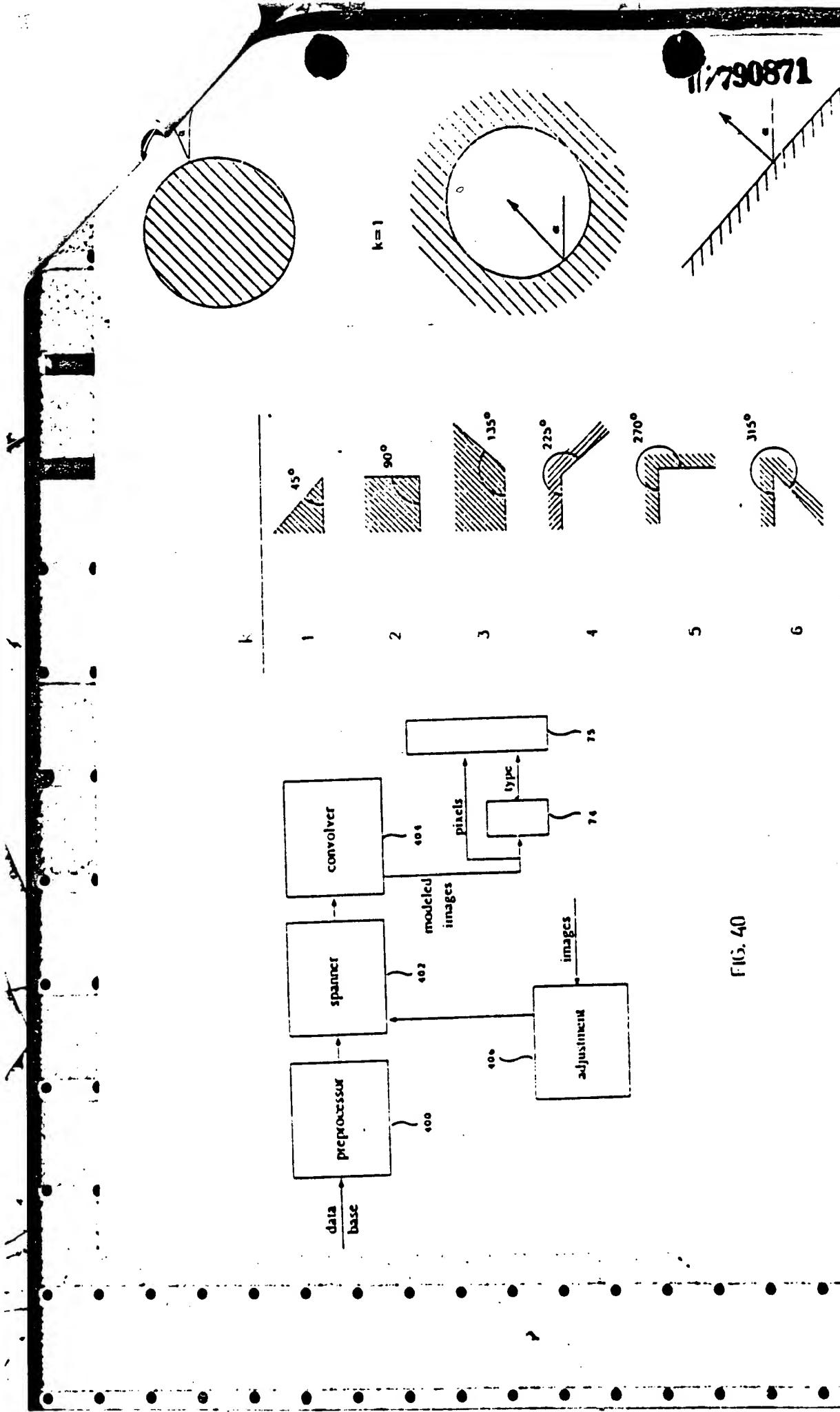


FIG. 42

38/41

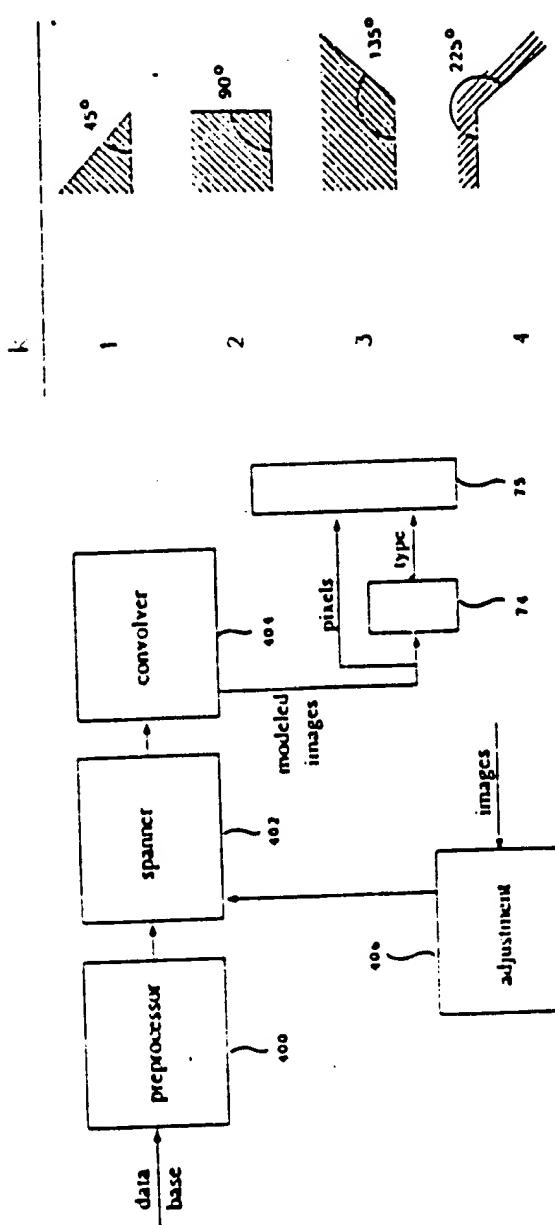


Fig. 40

11/790871

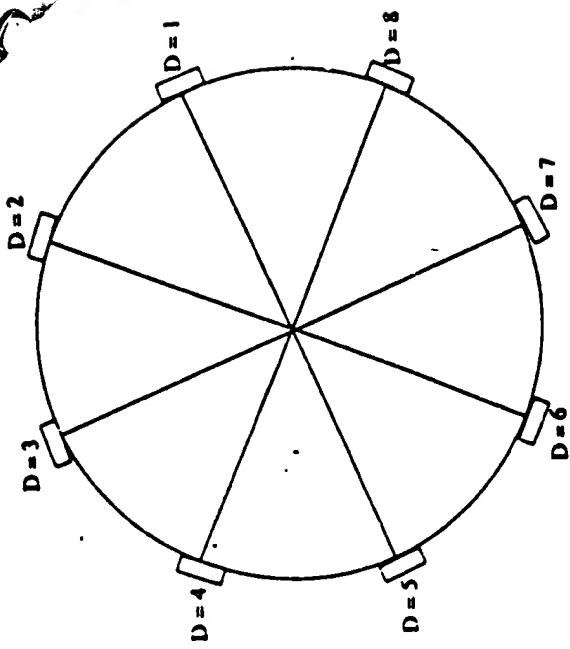
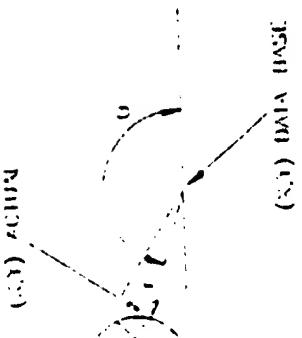


Fig. 43



CORNER SHIFT

FIG. 44

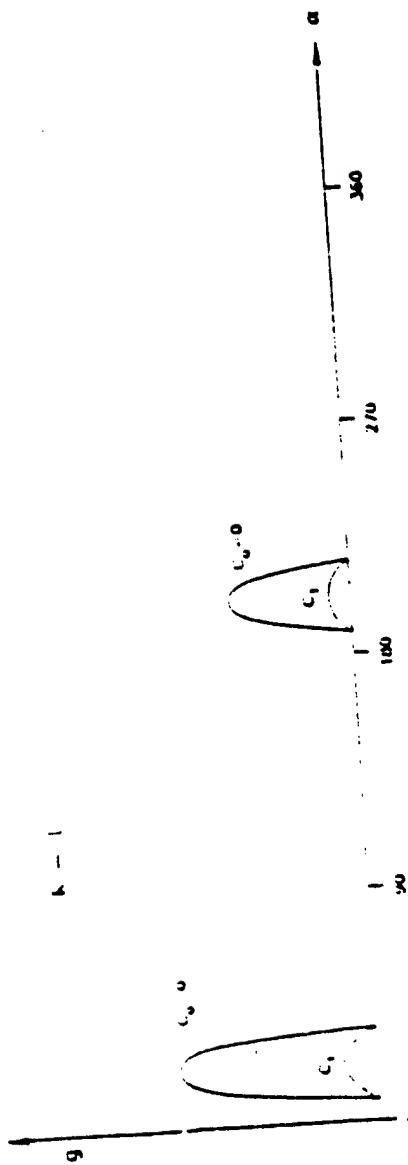


FIG. 45

11/790871

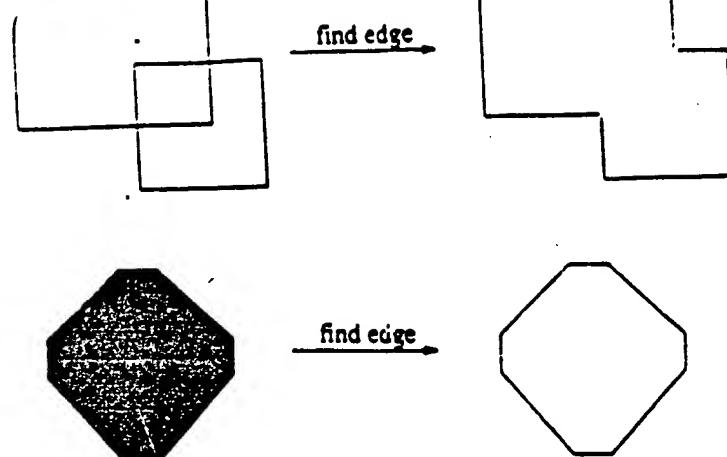


Fig. 46

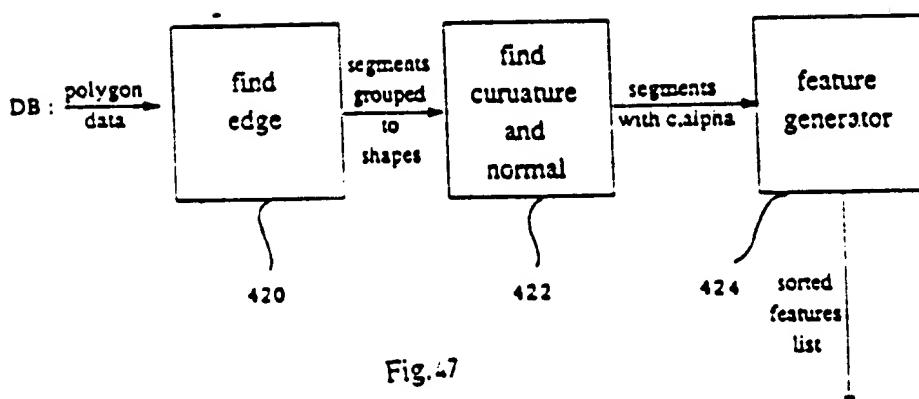


Fig. 47

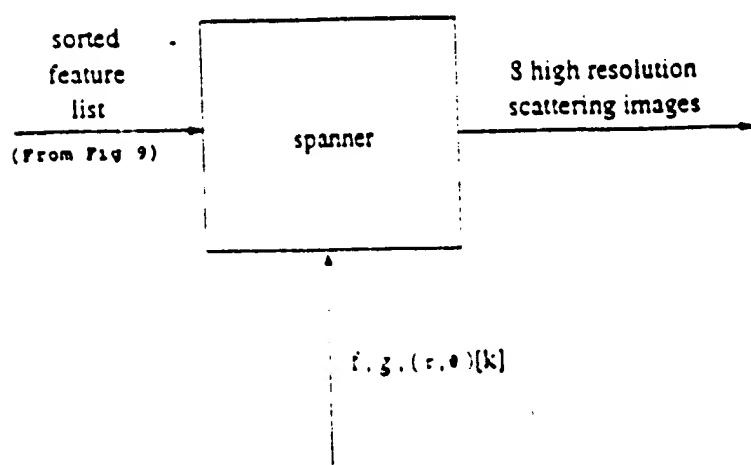


Fig. 48

117790871

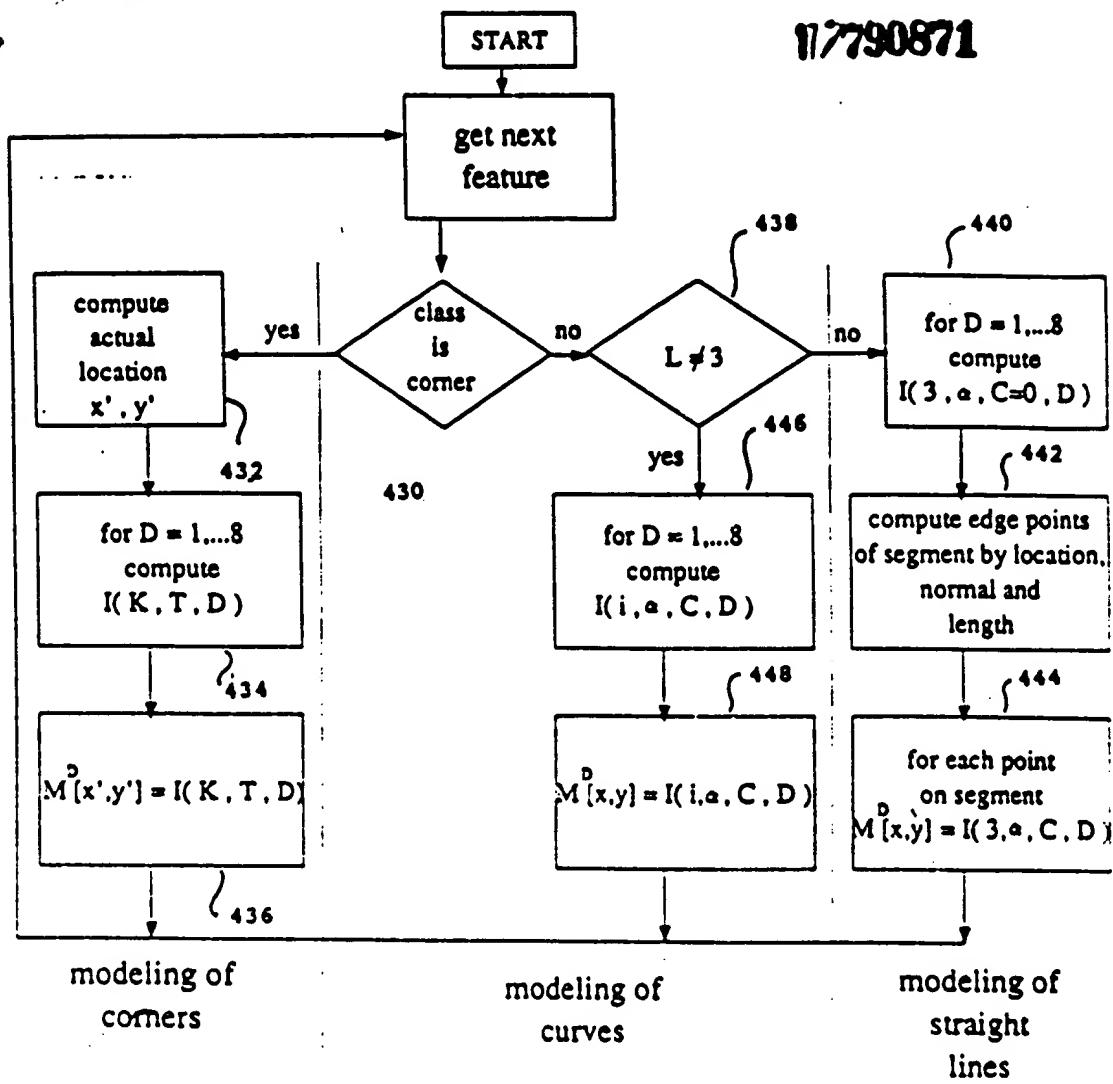


Fig.29 : spanner flow-chart

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- BLACK BORDERS**
- IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- FADED TEXT OR DRAWING**
- BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- SKEWED/SLANTED IMAGES**
- COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- GRAY SCALE DOCUMENTS**
- LINES OR MARKS ON ORIGINAL DOCUMENT**
- REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- OTHER:** _____

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.